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**High performance, low dissipation
QCL across the Mid-IR range.**

08.09.14 / Alfredo Bismuto

Introduction

Mid-IR spectral range: applications

Alpes Lasers SA overview

Single mode sources

Fabrication process

QCLs for mass production (device length impact)

Impact of front reflective coating on short devices

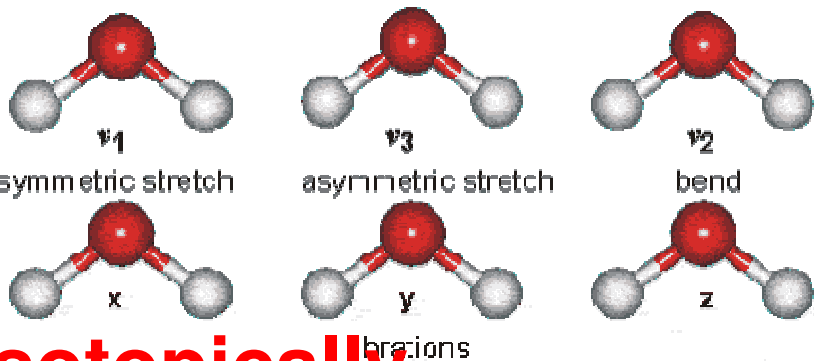
DFB sources below 1W between 4.5-9.3 μm

High power DFBs

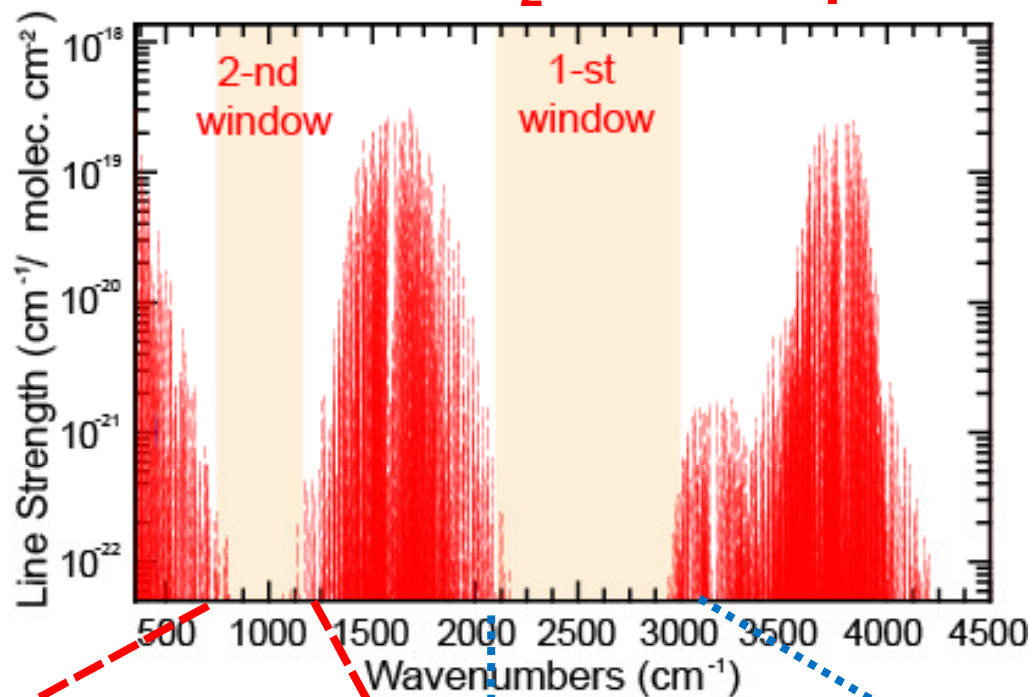
Conclusion and next steps

Mid-IR range (2-20 μm)

Strong molecular absorptions (orders of magnitude bigger than in the NIR-range)

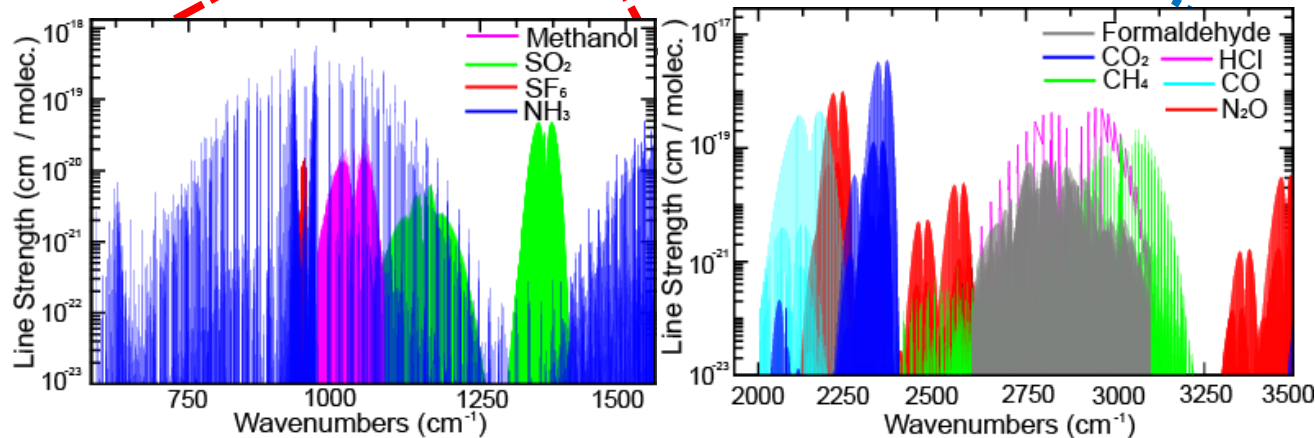


H₂O absorption

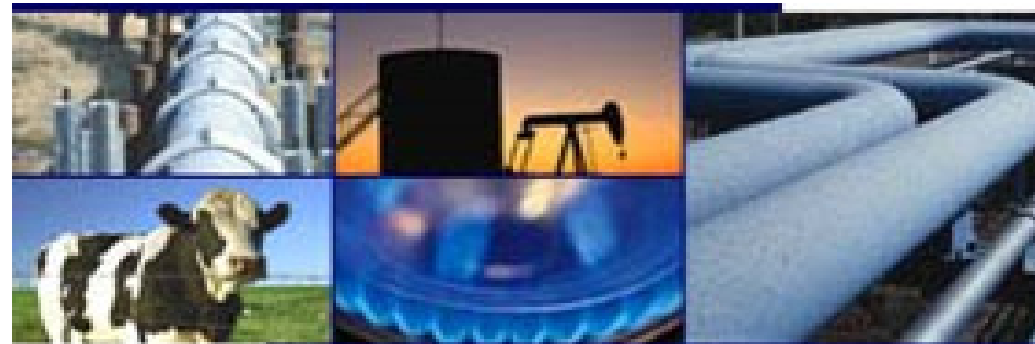


Isotopically sensitive

NO_2 , CO ,
 CO_2 , CH_4 , NH_3 ,
 CH_2CO , O_3 , N_2O
 HF , HCl



ALPES LASERS Applications



- **Environmental gas monitoring**

- . Atmospheric chemistry
- . Volcanic emissions

- **Urban and Industrial emission control**

- . Industrial plants
- . Automobile and Aircraft emissions
- . Combustion process control

- **Rural emission measurements**

- **Biochemical and Clinical diagnostics**

- . Breath analysis (NO, CO, CH₄, S)
- . Glucose level control (in-vivo)



A killer application is still missing...why?

•Laser sources

- .Low efficiency (~10%) compared to diode lasers (~50%)**
- .High electrical dissipation ($W_{el} > 1W$)**
- .Nb of lasers per wafers still low (long lasers & small wafers)**
- .Fabrication is still expensive**

•Photonics

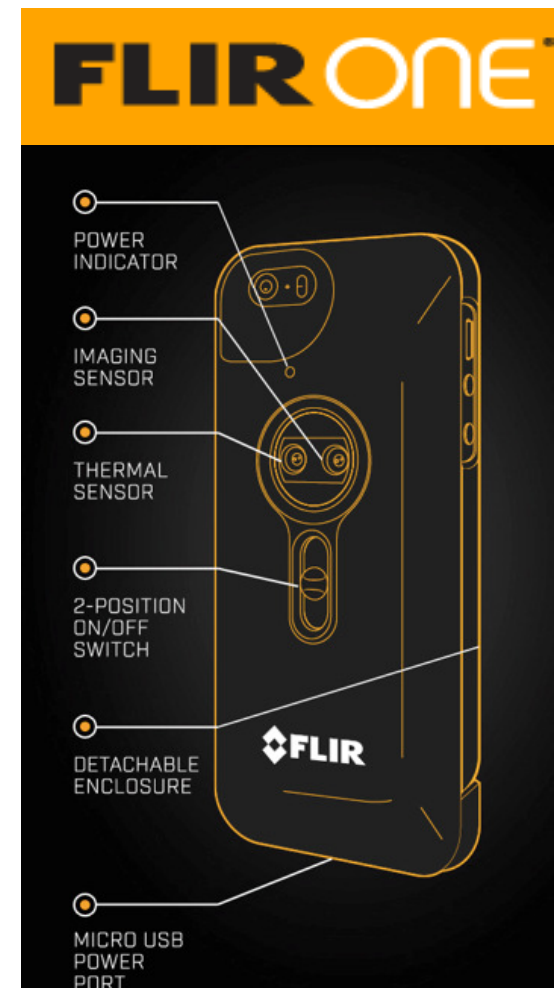
- .Difficult to do photonic integration**
- .Optical elements expensive (lenses/windows/fibers)**
- .Detectors less sensitive and more expensive**



Things are changing....

**FLIR introduced the FLIR ONE project
a IR camera compatible with the Iphone
The cameras should cost less than 350 \$**

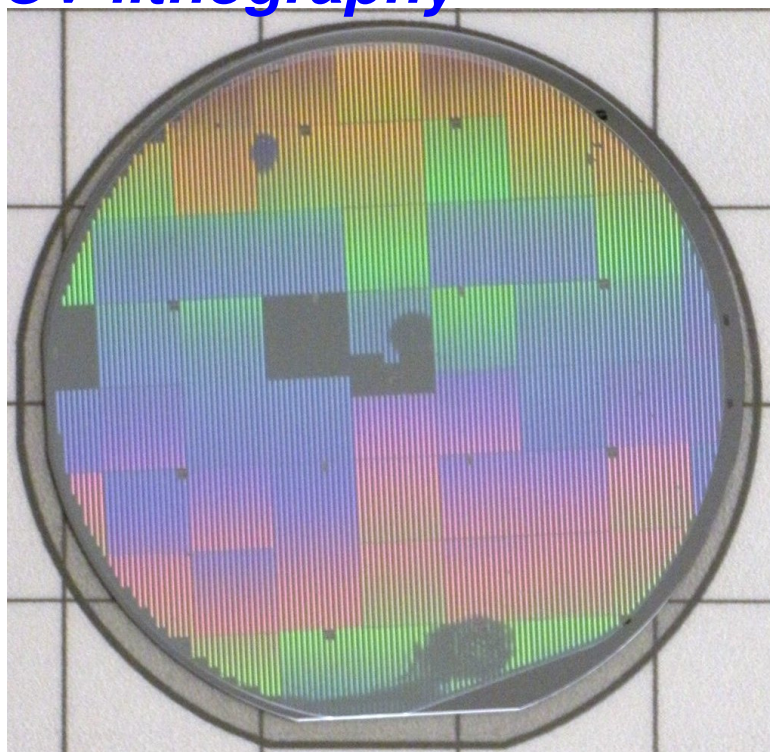
**Many big company are trying to develop
products in the IR**



Alpes Lasers

- founded in 1998
- 21 employees (11 PhD, 5 eng.)
- New product design team growing
- Fabless component manufacturer
- Widening products portfolio
- 2400+ sold lasers

UV-lithography



DFB grating during fabrication

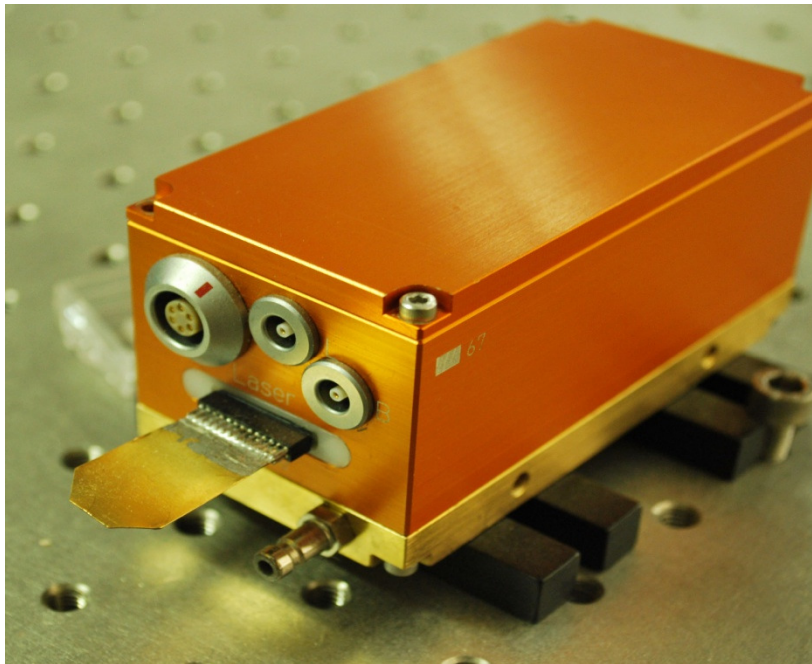
		C7 1.9655 0.8%	D7 1.9145 1.6%	E7 1.8085 2.0%	F7 1.9255 1.6%	G7 1.8765 0.8%		
	B6 1.836 1.2%	C6 1.948 2.0%	D6 1.8645 2.0%	E6 1.8765 2.0%	F6 1.7765 2.0%	G6 1.8695 2.0%	H6 1.933 1.2%	
A5 1.887 0.4%	B5 1.741 2.0%	C5 1.7375 2.0%	D5 1.741 2.0%	E5 1.8835 2.0%	F5 1.734 2.0%	G5 1.746 2.0%	H5 1.887 2.0%	I5 1.7765 0.4%
A4 (LOCK) 00.00000 1.0%	B4 1.8395 2.0%	C4 1.8835 2.0%	D4 (LOCK) 00.00000 2.0%	E4 1.848 1.5%	F4 1.9555 2.0%	G4 1.8765 2.0%	H4 1.873 2.0%	I4 1.7375 1.0%
A3 1.831 1.0%	B3 1.789 2.0%	C3 1.873 2.0%	D3 1.88 2.0%	E3 1.7375 1.5%	F3 1.7565 2.0%	G3 1.887 2.0%	H3 1.799 2.0%	I3 1.843 1.0%
A2 1.746 0.5%	B2 1.9045 2.0%	C2 1.843 2.0%	D2 1.892 2.0%	E2 1.751 2.0%	F2 1.836 2.0%	G2 1.8395 2.0%	H2 1.7615 2.0%	I2 1.9655 0.5%
	B1 1.8695 1.4%	C1 1.9405 2.0%	D1 1.897 2.0%	E1 1.8185 2.0%	F1 1.88 2.0%	G1 1.8595 2.0%	H1 1.826 1.4%	
		C0 1.8545 1.1%	D0 1.724 1.9%	E0 1.729 2.0%	F0 1.7665 1.9%	G0 1.734 1.1%		

Proprietary design tool

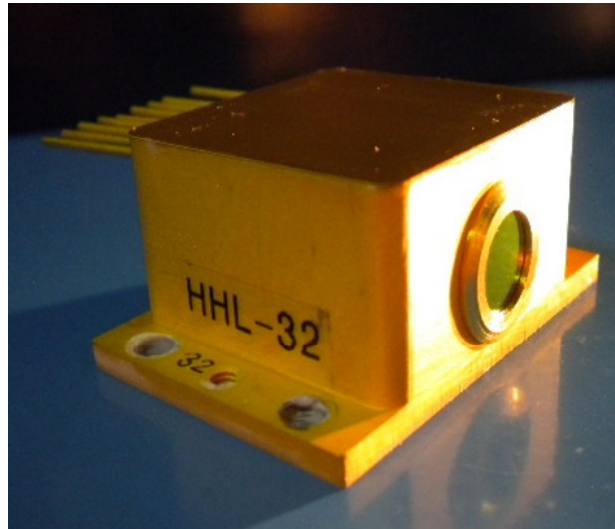
- Gratings written by standard lithography from 4-12 μm
- Many different wavelengths can be fabricated at once
- Efficient device mounting
- Full 2"- wafer process

ALPES LASERS QCL subsystems

鋳LLH



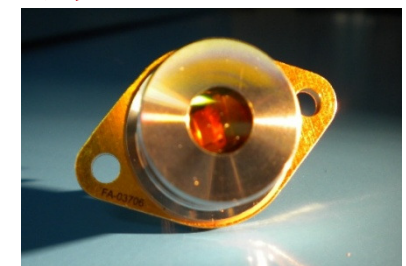
鋳HHL-L



鋳TO3-L



鋳TO3-W

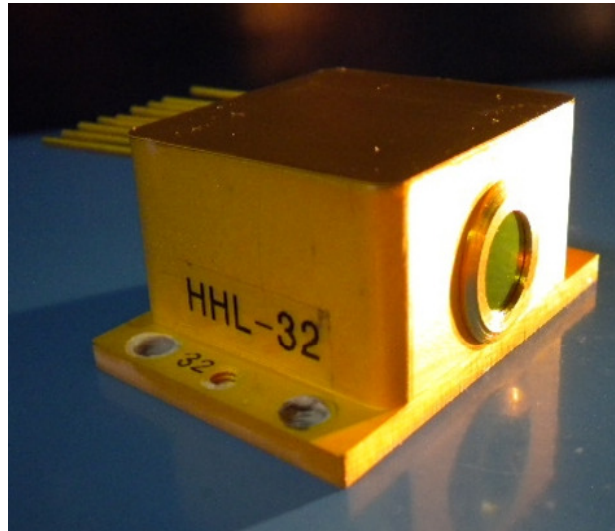


Used only in the initial testing phase

鋳LH



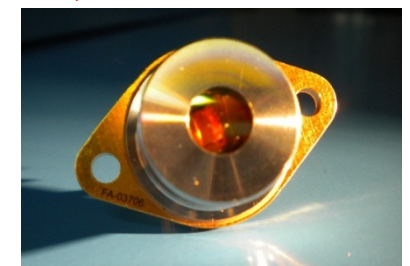
鋳HHL-L



鋳TO3-L



鋳TO3-W



Used only in the initial testing phase

鋳low consumption packages being
鋳validated (TO5, etc.)

Introduction

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Single mode sources

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QCLs for mass production (device length impact)

DFB sources below 1W between 4.5-8 μm

Impact of front reflective coating on short devices

High power DFBs

Conclusion and next steps

- .Most of QCLs have 5-15 W of electrical dissipation
- .Up to 100 W are needed to control the temperature
- .Optical power levels of few mW sufficient for many applications

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Research goal:

- .Low dissipation devices
- .Short chips
- .Still enough optical power for spectroscopy
- .

Advantages of short devices

- Low dissipation (Easy cw bar testing)
- More devices per wafer

- Low dissipation (Easy cw bar testing)
- More devices per wafer
- Probability of defect (λ) follows a Poissonian law
- Failure rate sensibly reduced with shorter lasers

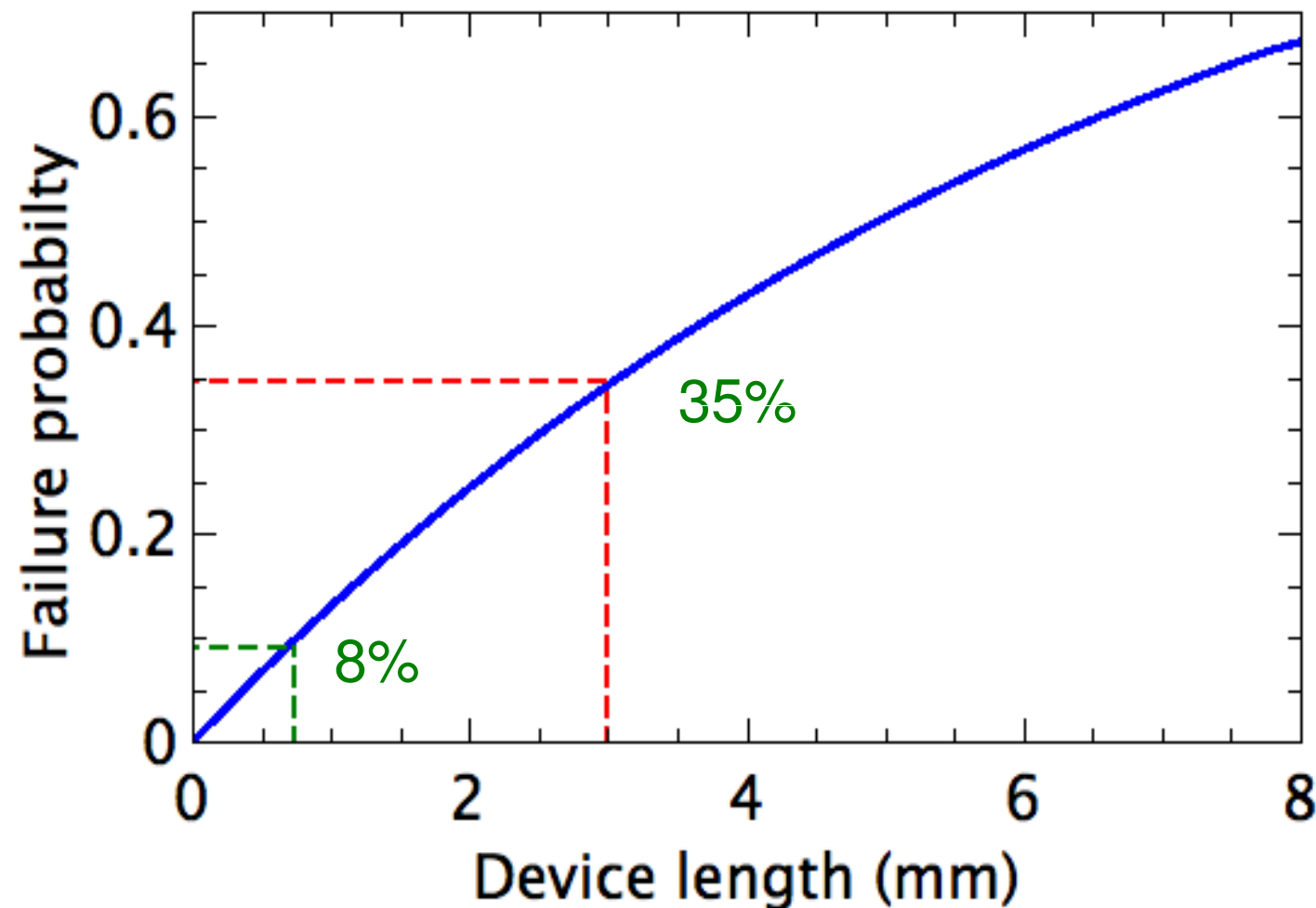
Number of defects

$$P = \sum_k \lambda^k \frac{e^{-\lambda}}{k!}$$

Probability
of major defect
in the laser wg

Advantages of short devices

Failure rate for mounted laser



Number of defects

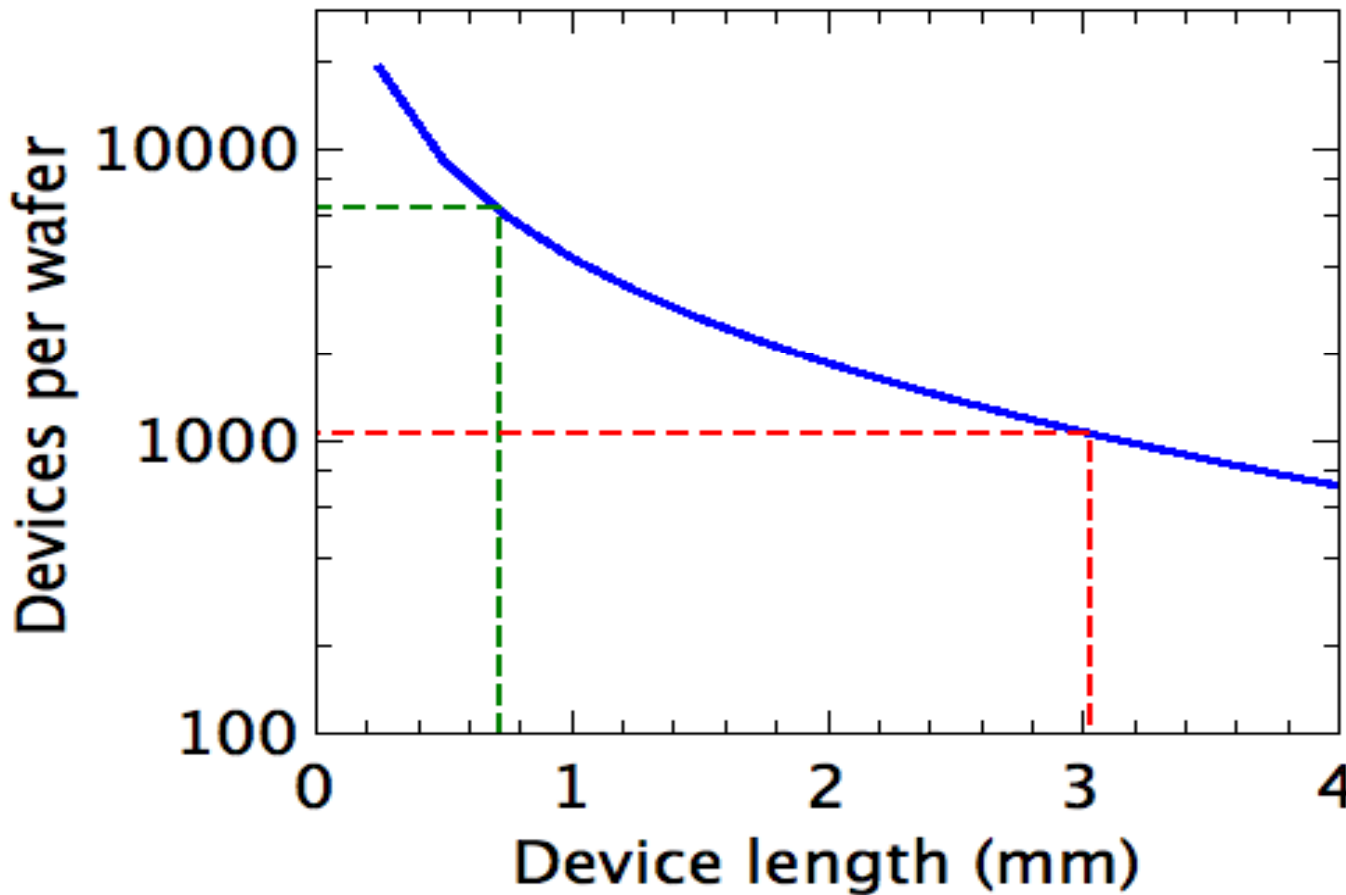
$$P = \sum_k \lambda^k \frac{e^{-\lambda}}{k!}$$

Probability of major defect in the laser wg

• Defect density estimated on the AL-Stock data (preliminary)

Advantages of short devices

Working lasers per 2" wafer



Number of defects

for many applications

$$P = \sum_k \frac{\lambda^k e^{-\lambda}}{k!}$$

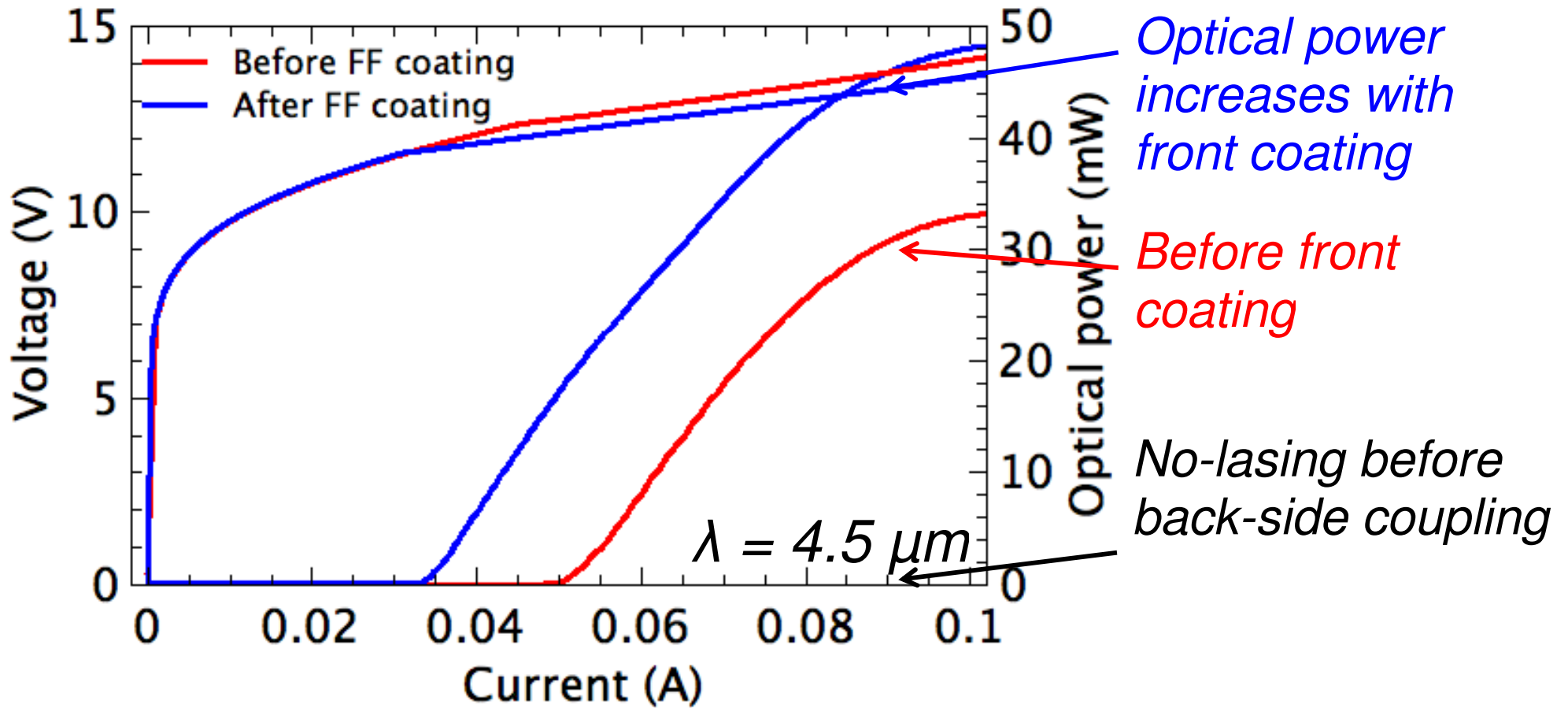
an law

Probability
of major defect
in the laser wg

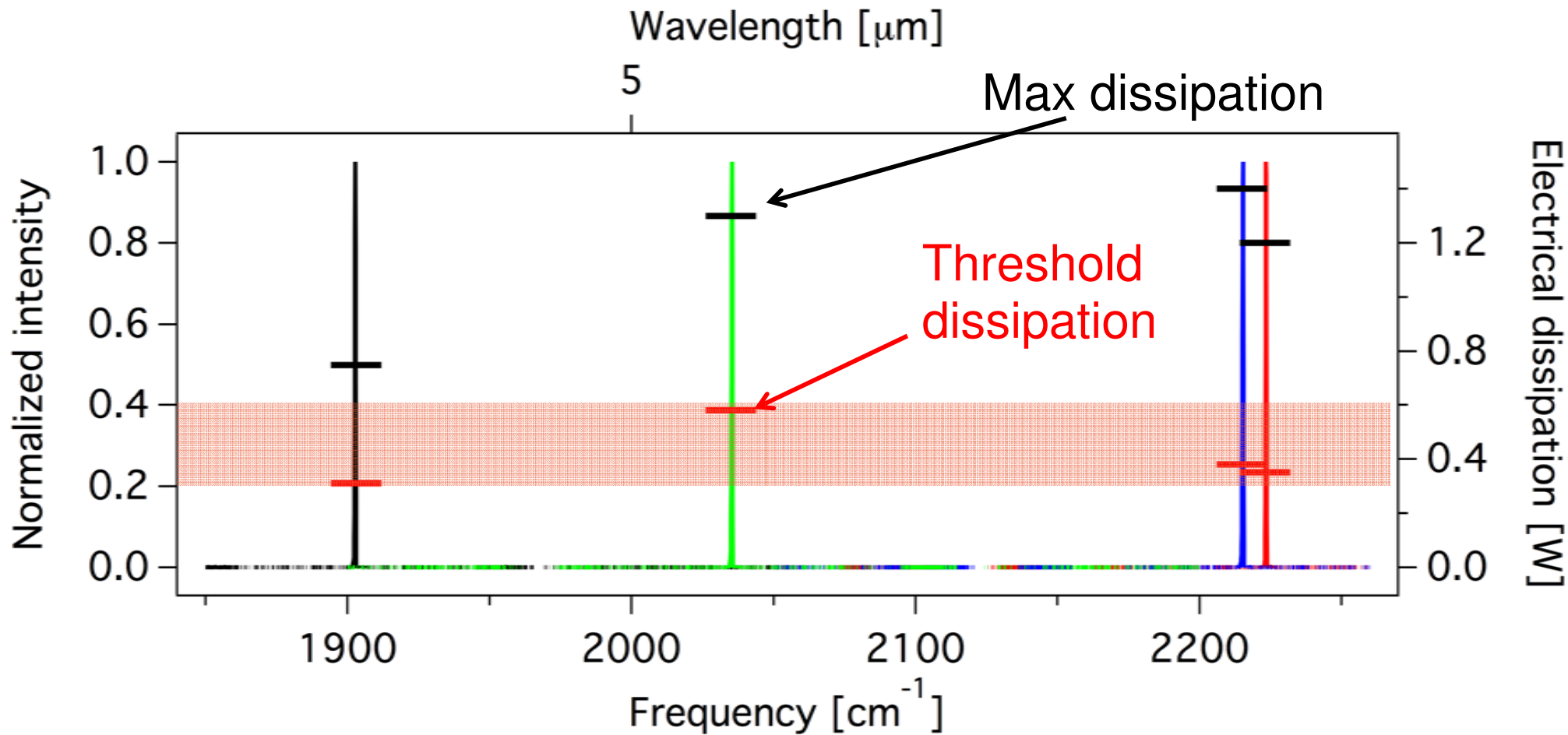
Doublefold impact on the number of chips/wafer

- .Starting range 4.5 μm and 5.5 μm
- .Optimize the grating coupling to obtain both **low consumption DFBs** and **high power DFBs** on the **same wafer**
- .*750 μm long devices, 3-4 μm wide*
- .Back-facet HR coating
- .Partial front HR coating

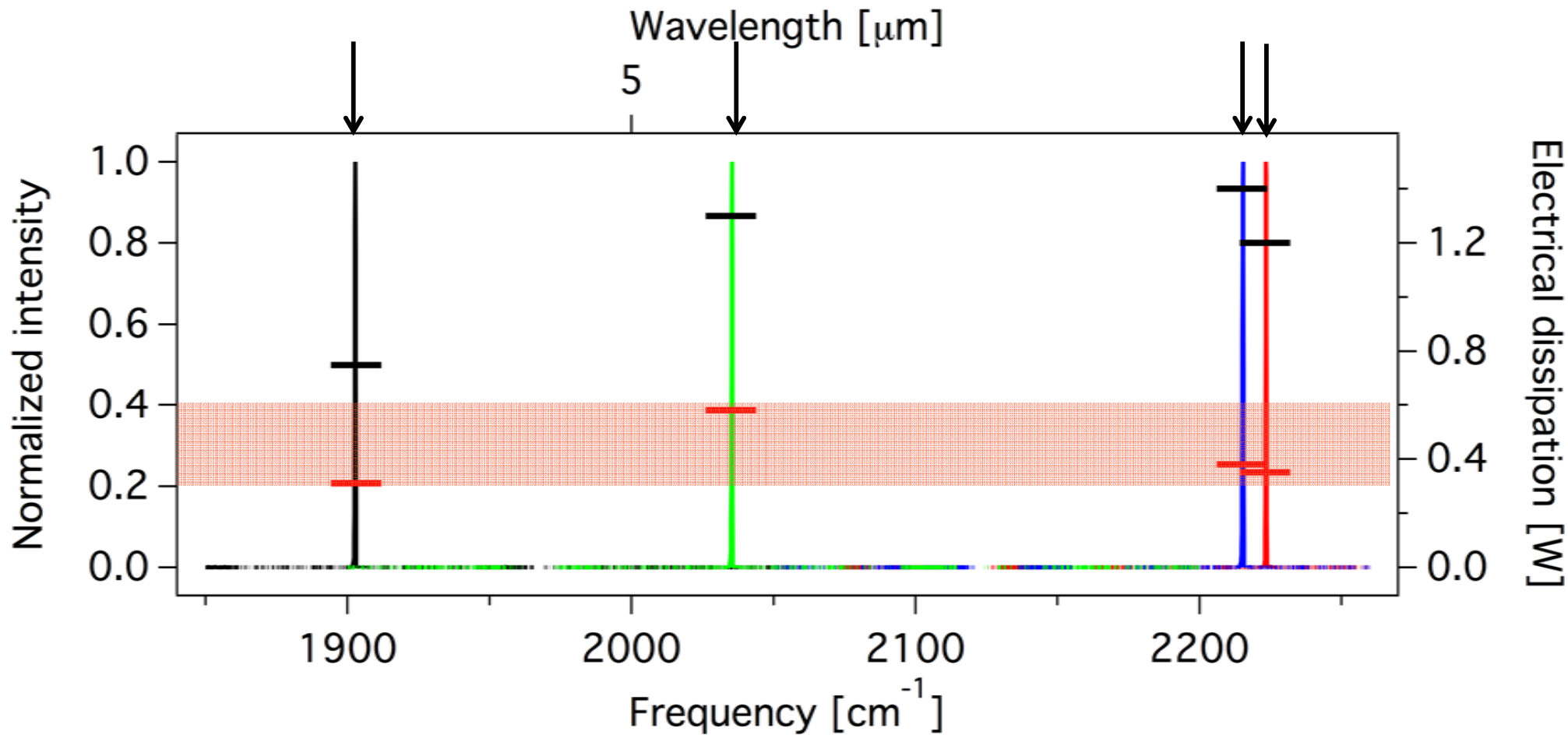
Front HR coating (dielectric)



750 μm long devices
3 μm wide ridge

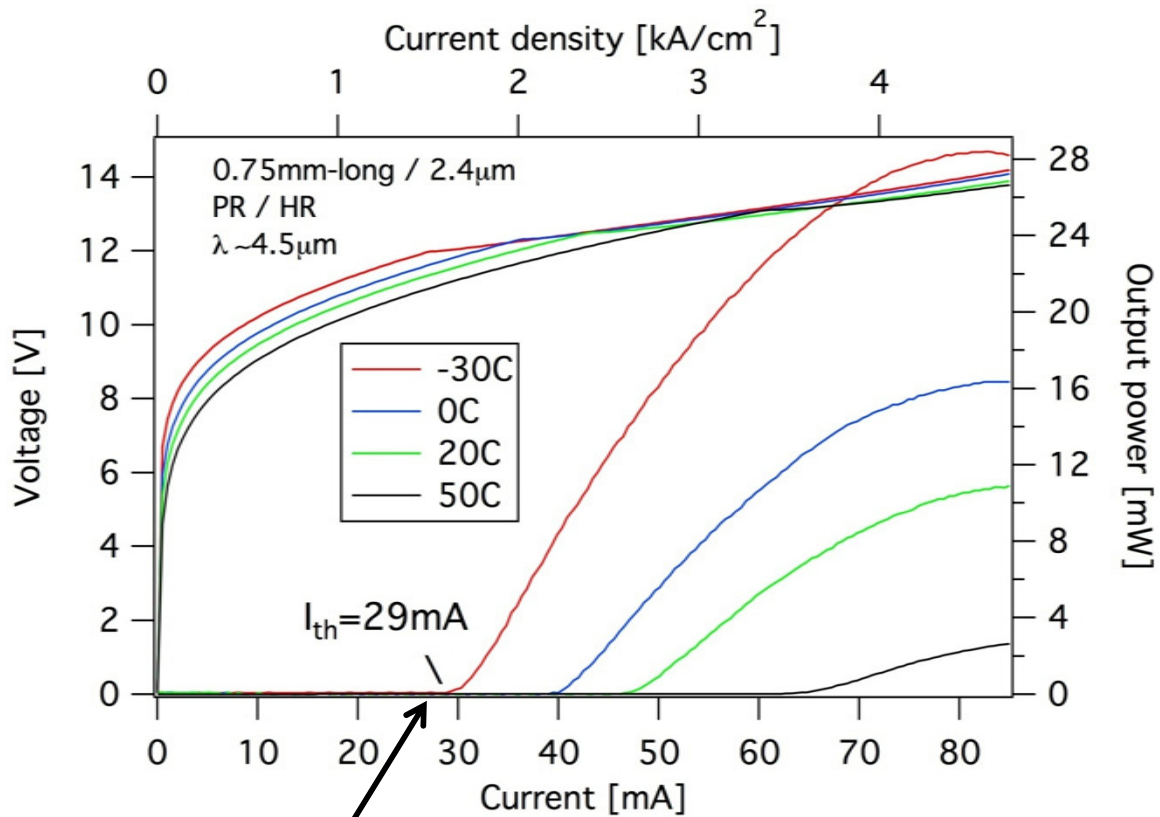


- .Dissipation at threshold as low as 0.3W
- .Max consumption < 1.4W between 4.5 μm and 5.3 μm

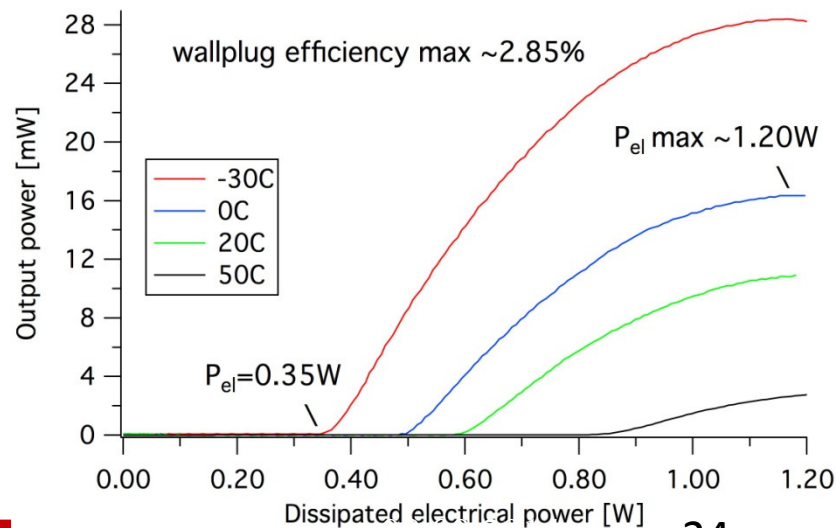
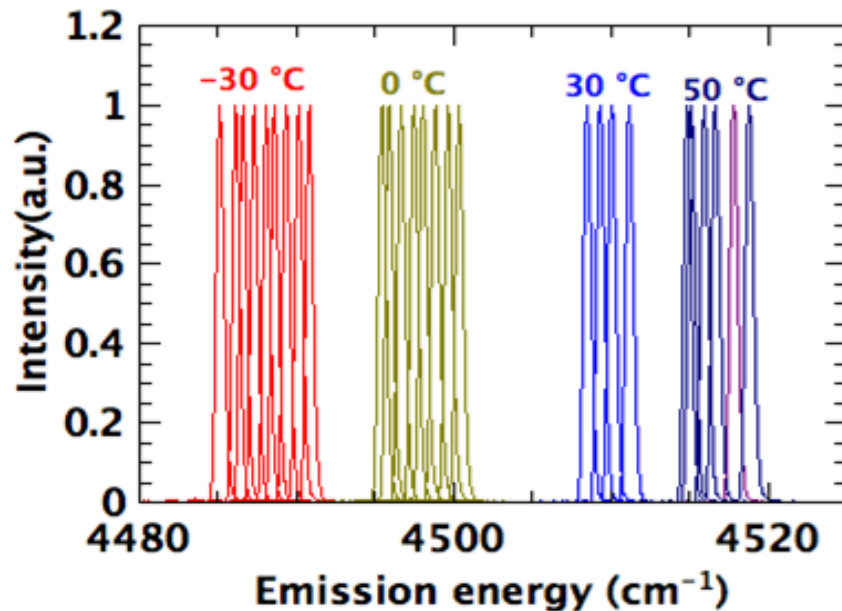


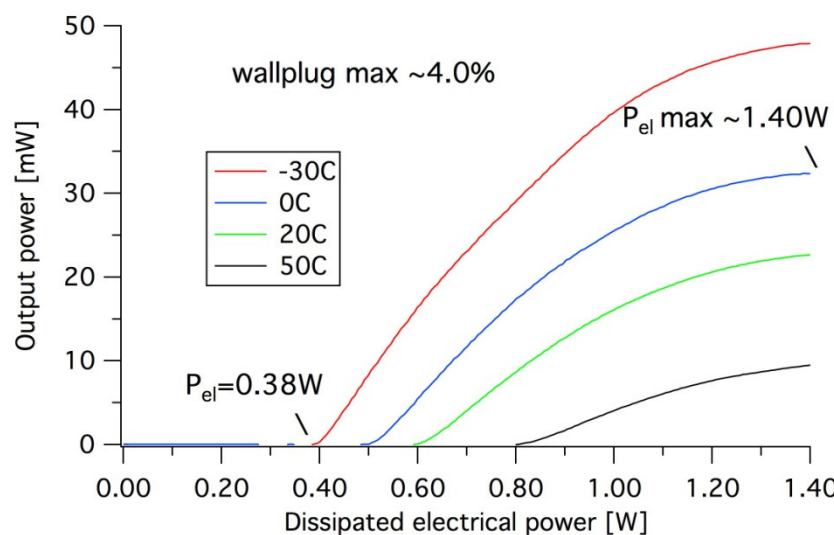
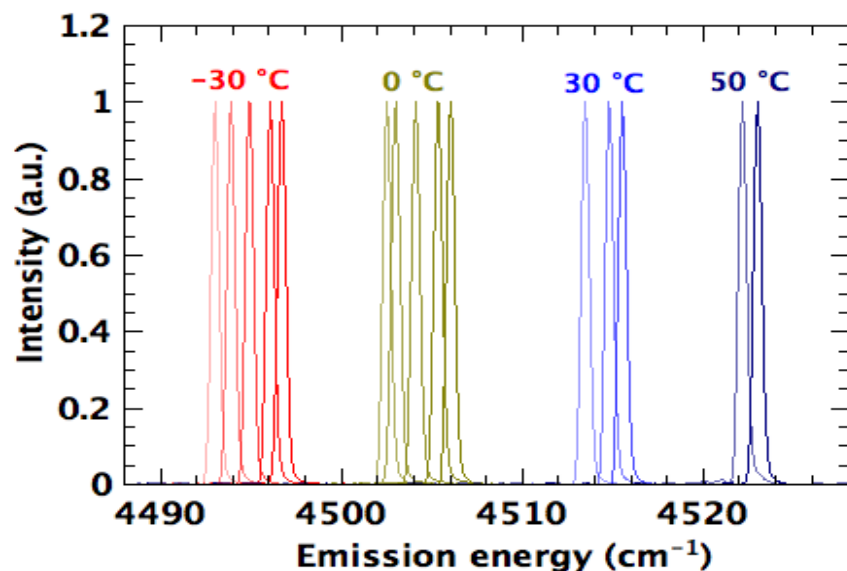
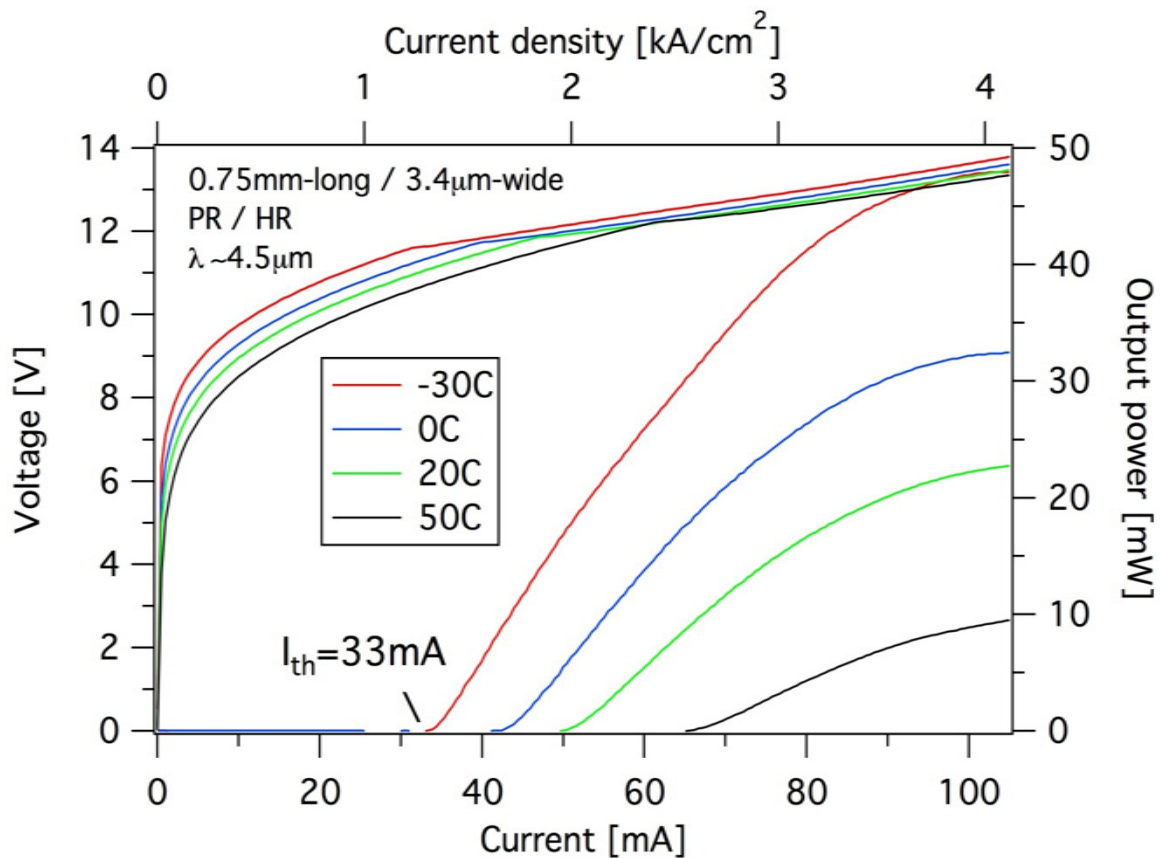
- Dissipation at threshold as low as 0.3W
- Max consumption < 1.4W between 4.5 μm and 5.3 μm

Low-dissipation DFB devices at 4.5 μm



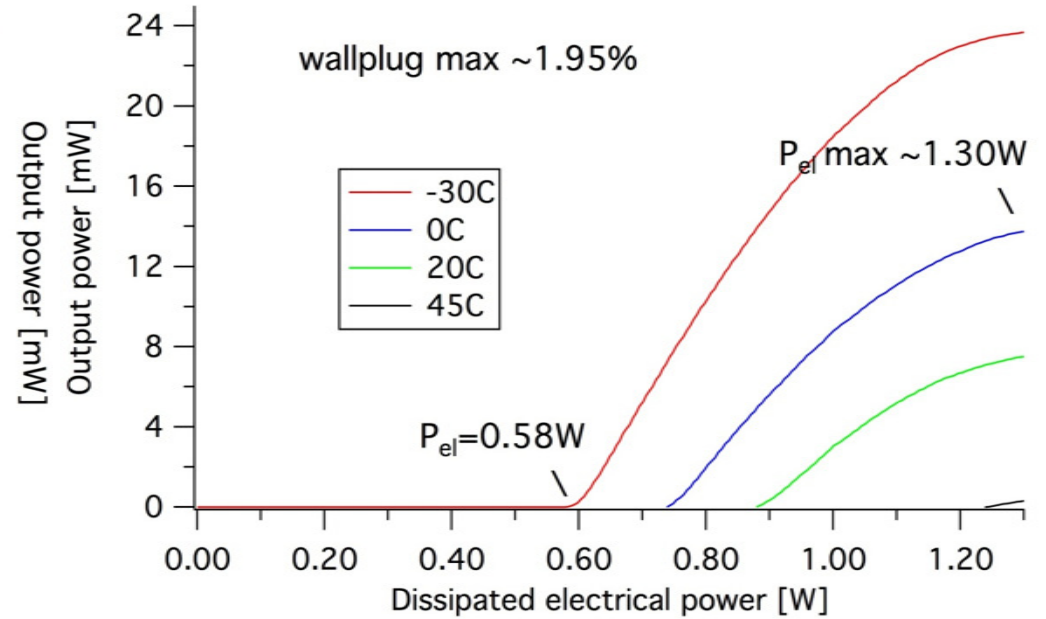
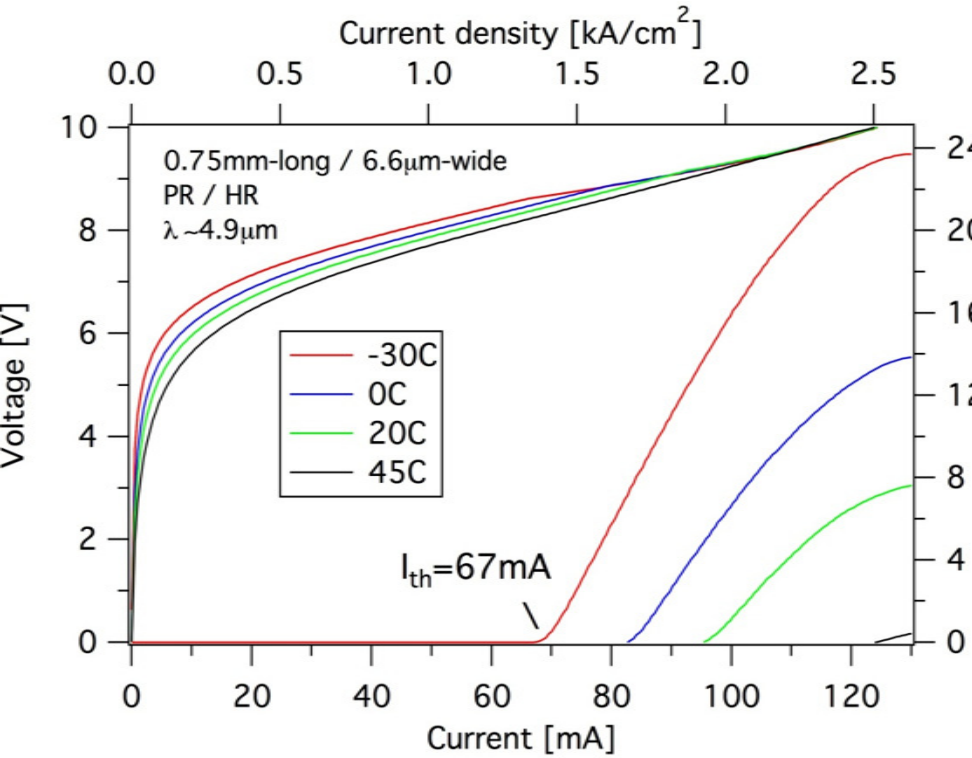
- very low threshold current : **29mA**
- P_{el} max \sim **1.2W**
- Single mode



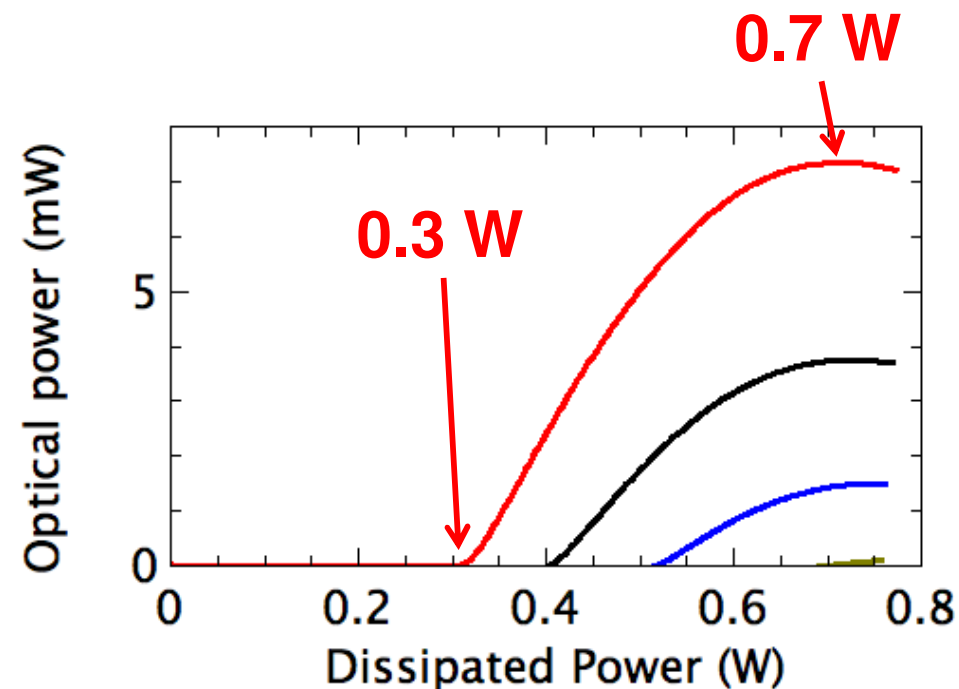
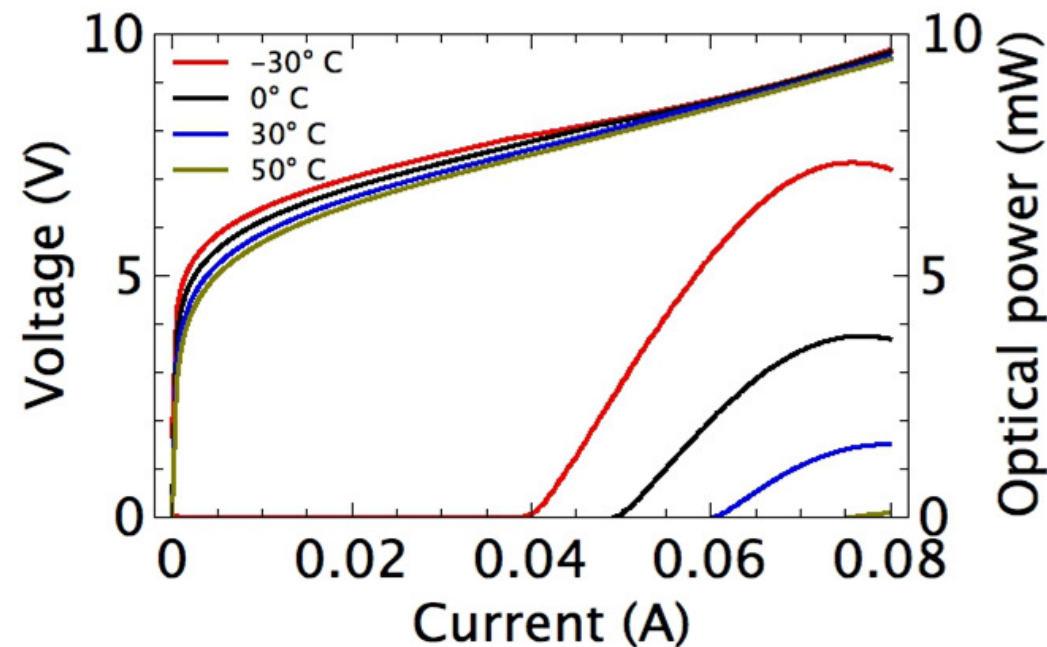
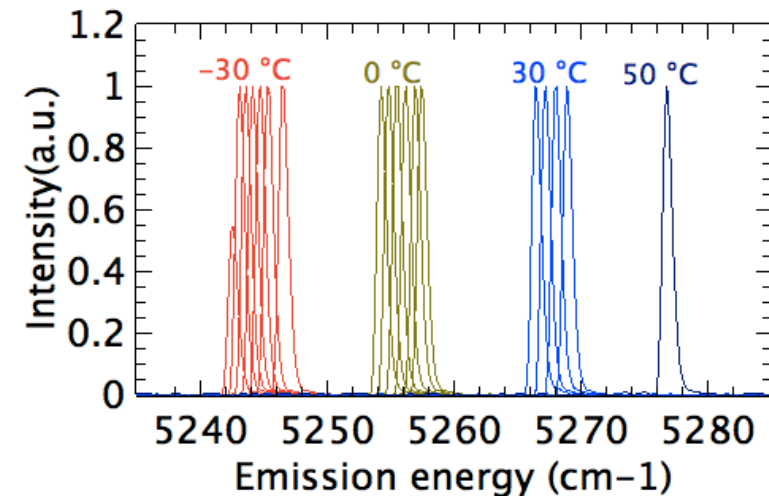


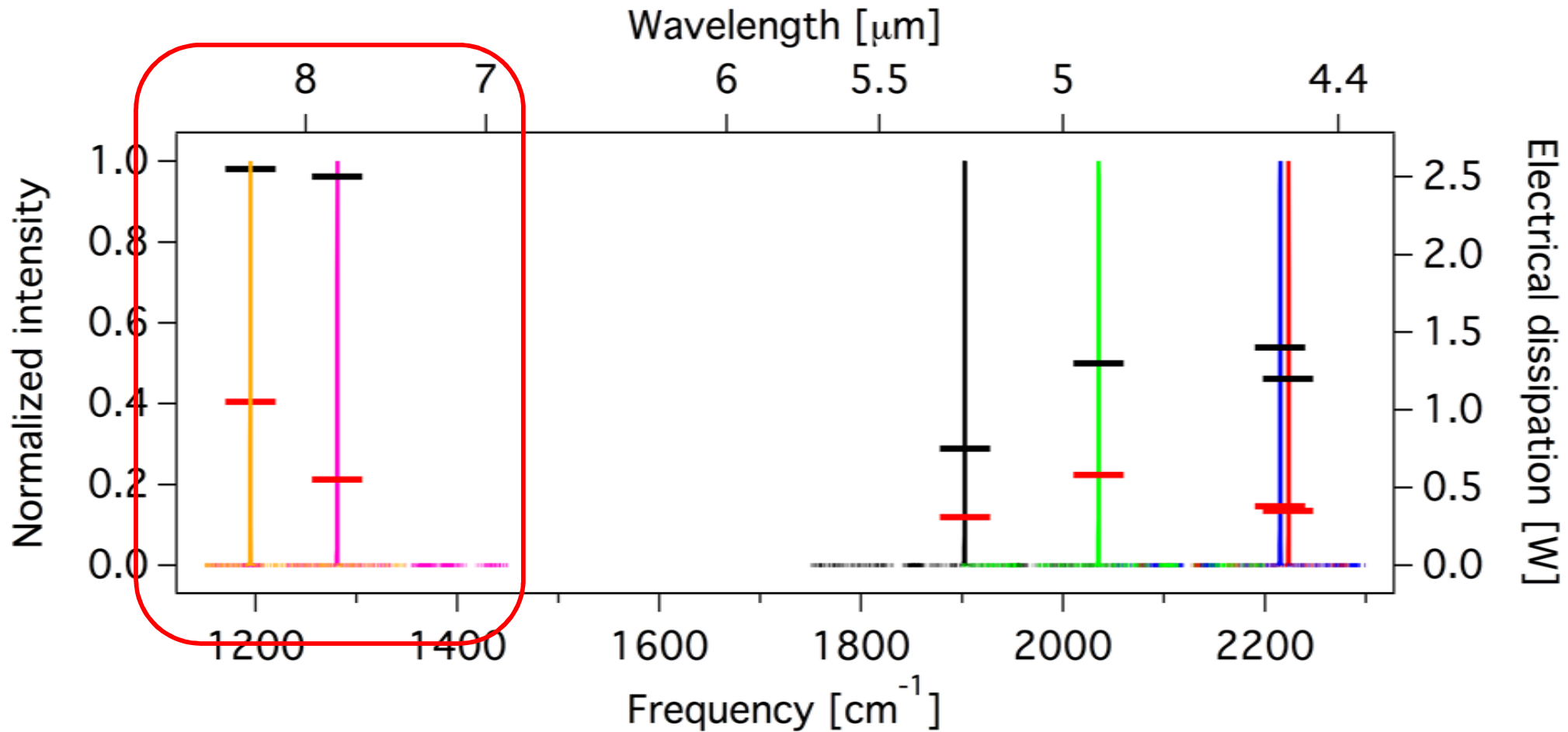
- opt power up to **48mW**
- $P_{el} \text{ max } \sim 1.4\text{W}$
- Single mode

Low-dissipation DFB devices at 4.90 μ m

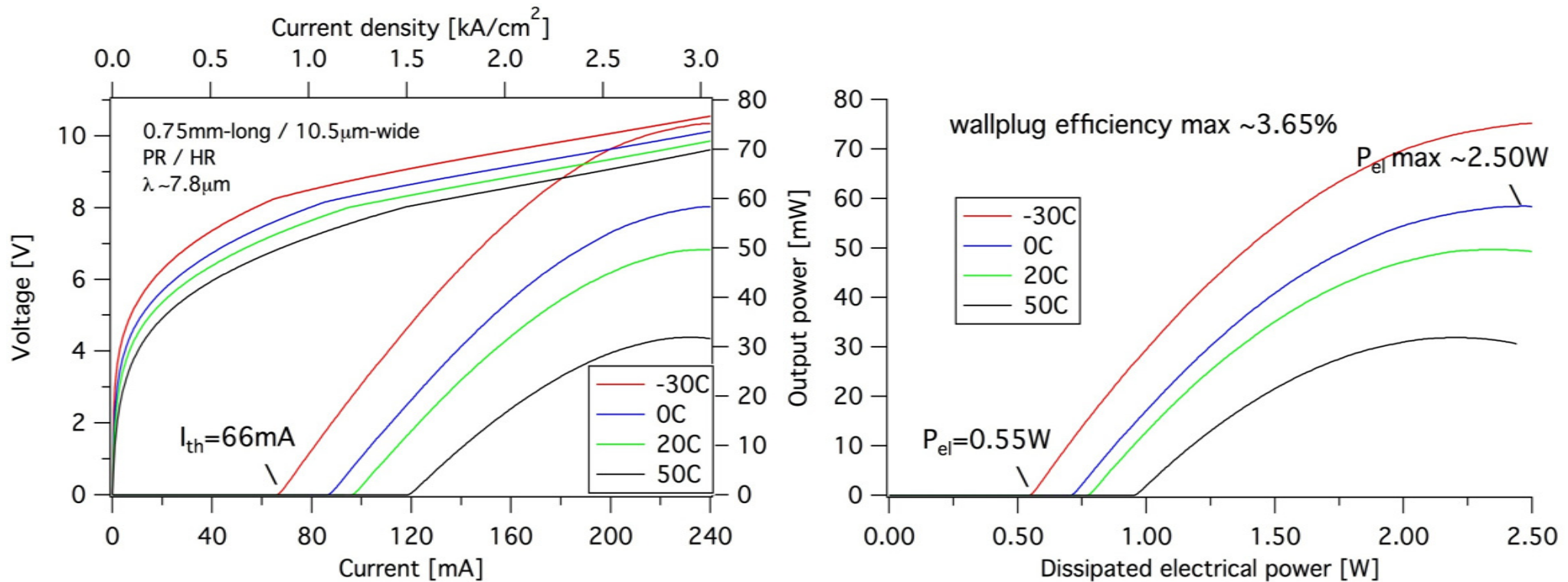


- Gain starving (too low doped structure)
- Electrical dissipation as low as 0.3 W
- No cooling needed
- Max dissipation 0.7 W

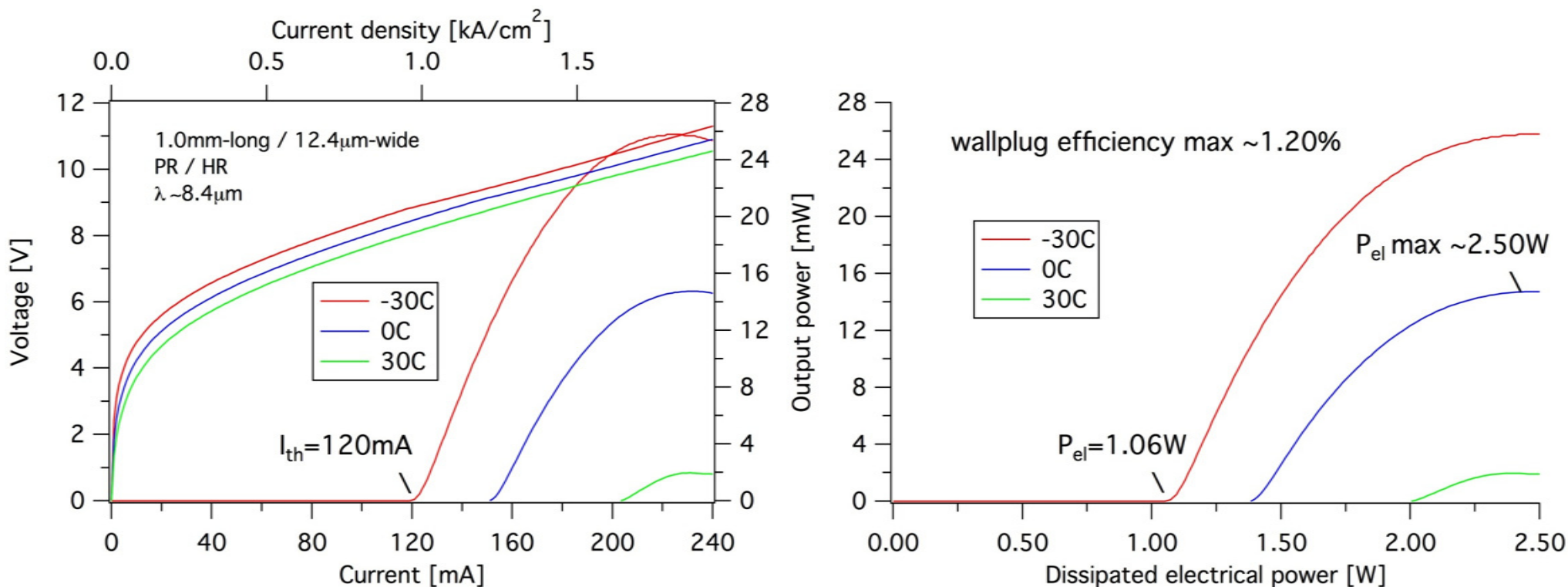




• Max consumption < 2.6W between 4.5 μm and 8.4 μm

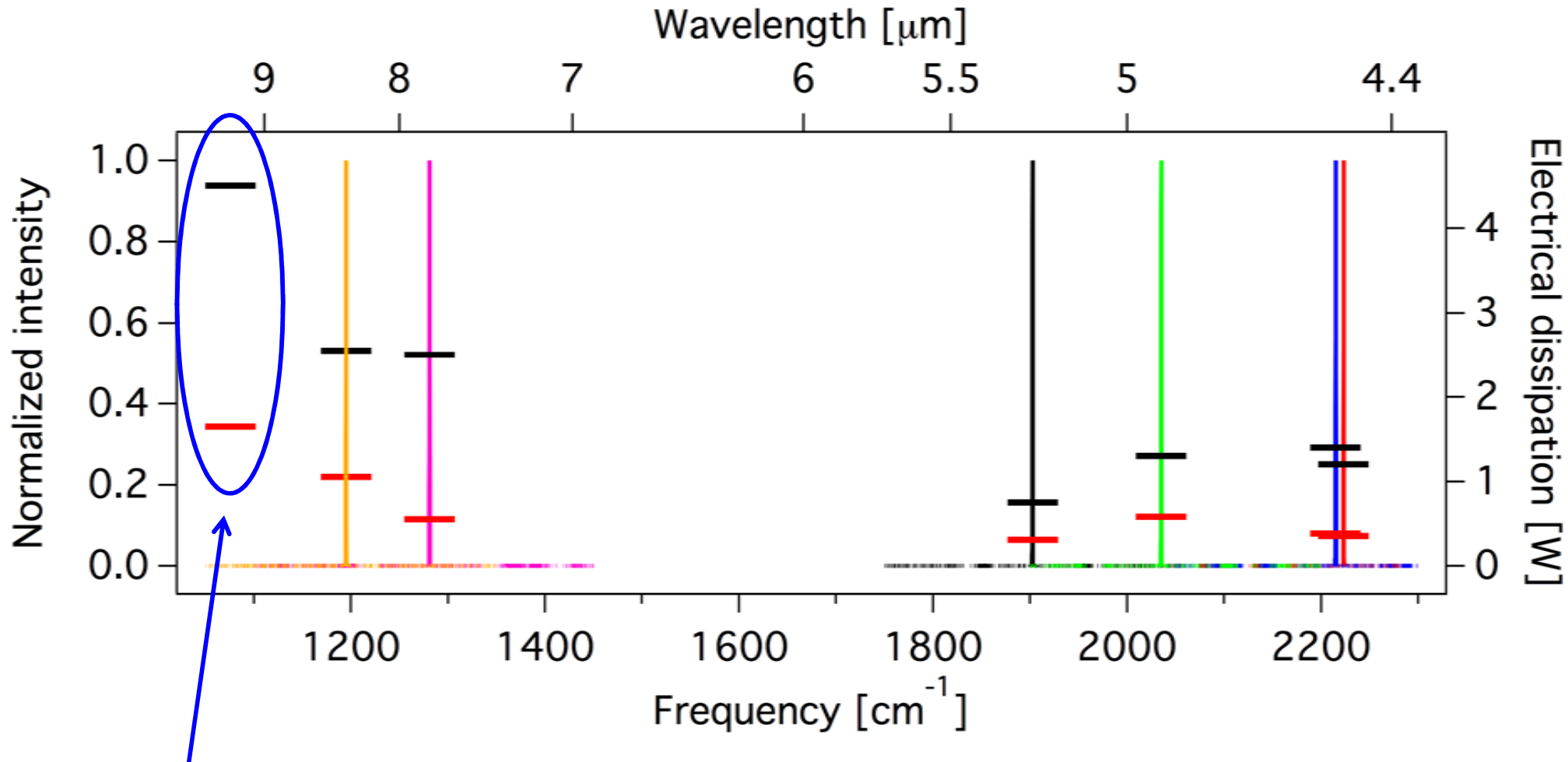


- Very low threshold current : 66 mA
- Very low threshold power : **0.55 W**
- $P_{\text{max}} > 70 \text{ mW}$ / huge dynamical range



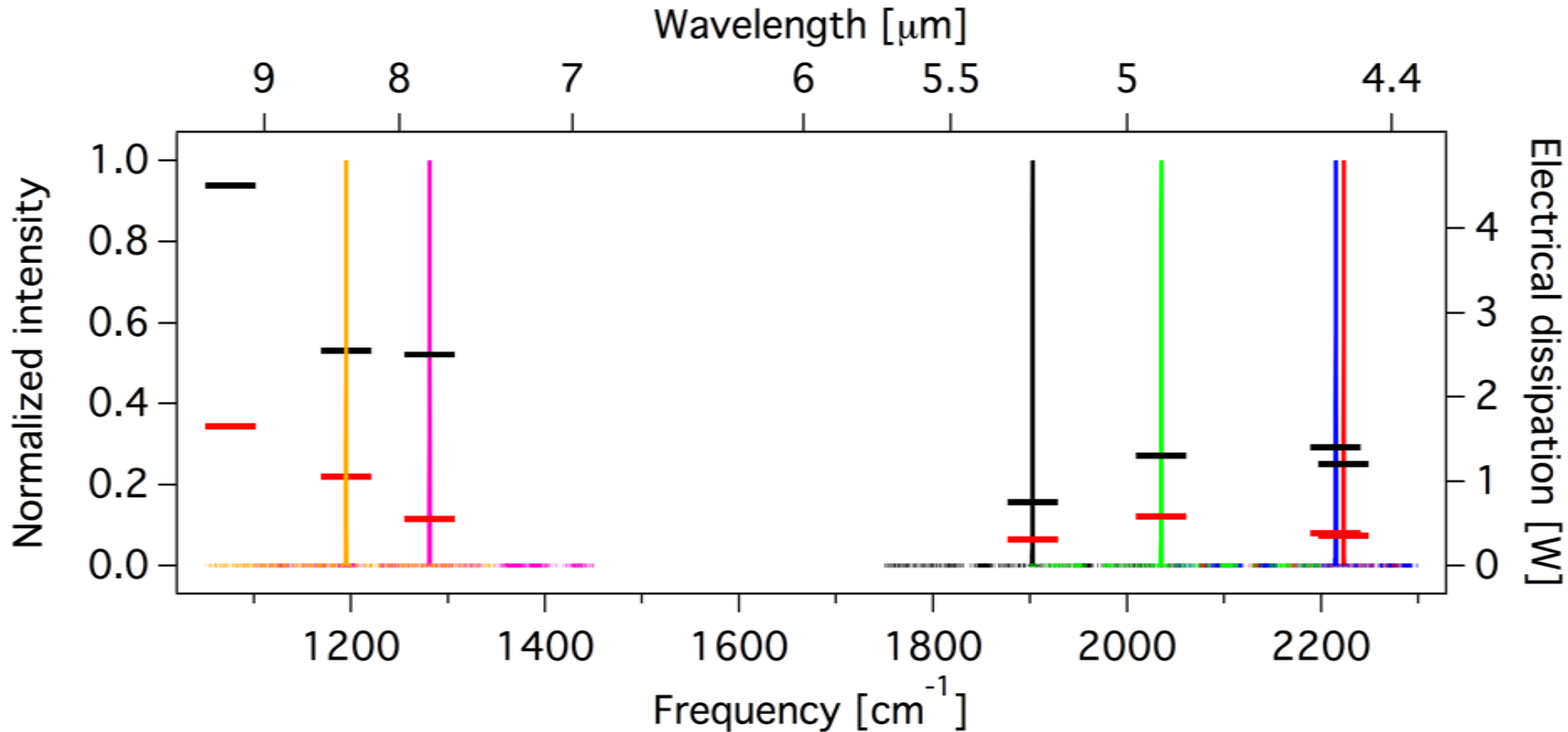
- did not lase while uncoated/HR !
- As for the 4.9 μm case the design is too little doped
- low threshold power : 1.06W

Low consumption devices (9.3 μm)



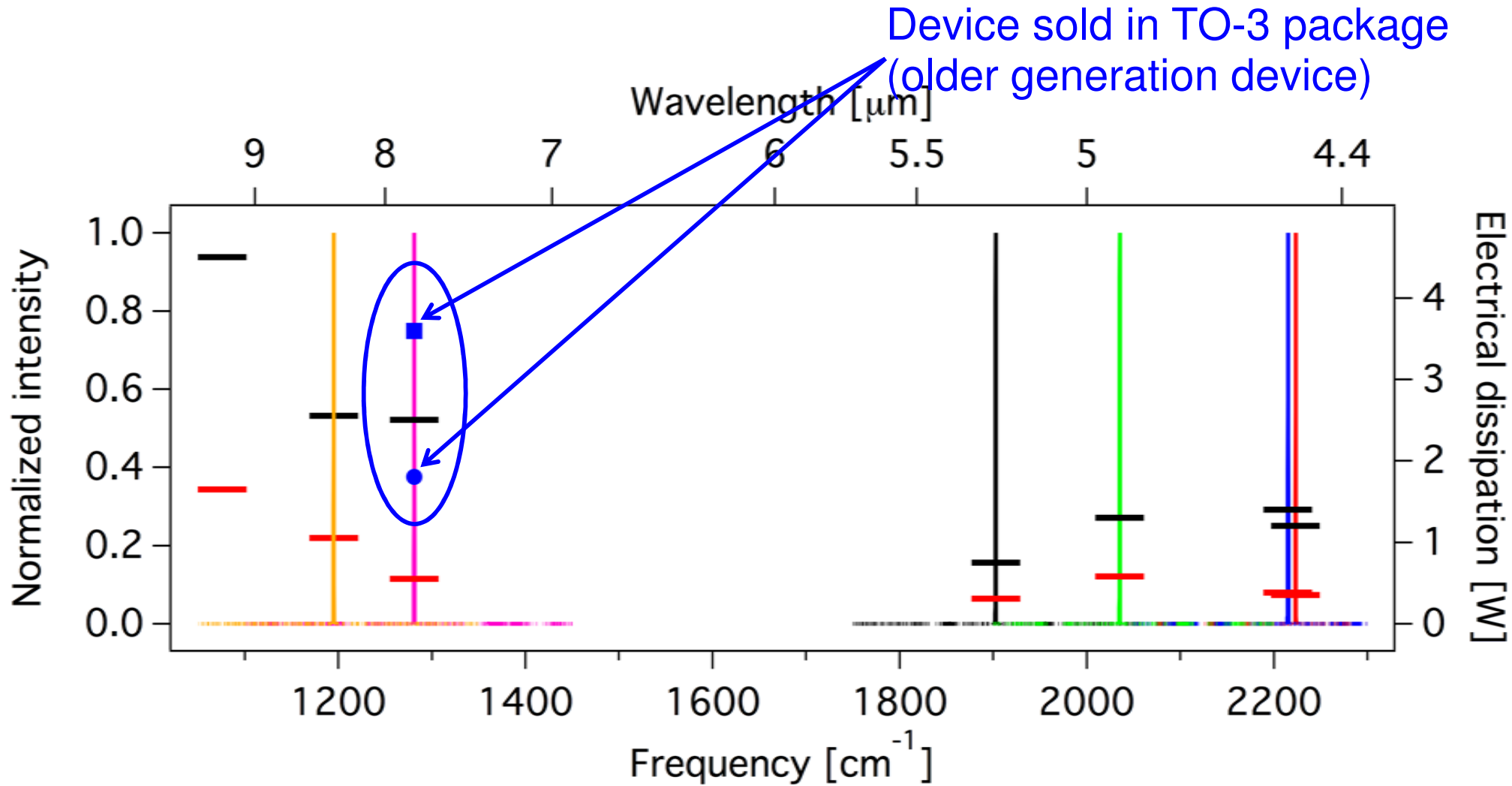
preliminary results at 9.3 μm (only HR on back facet)

FF coating being developed

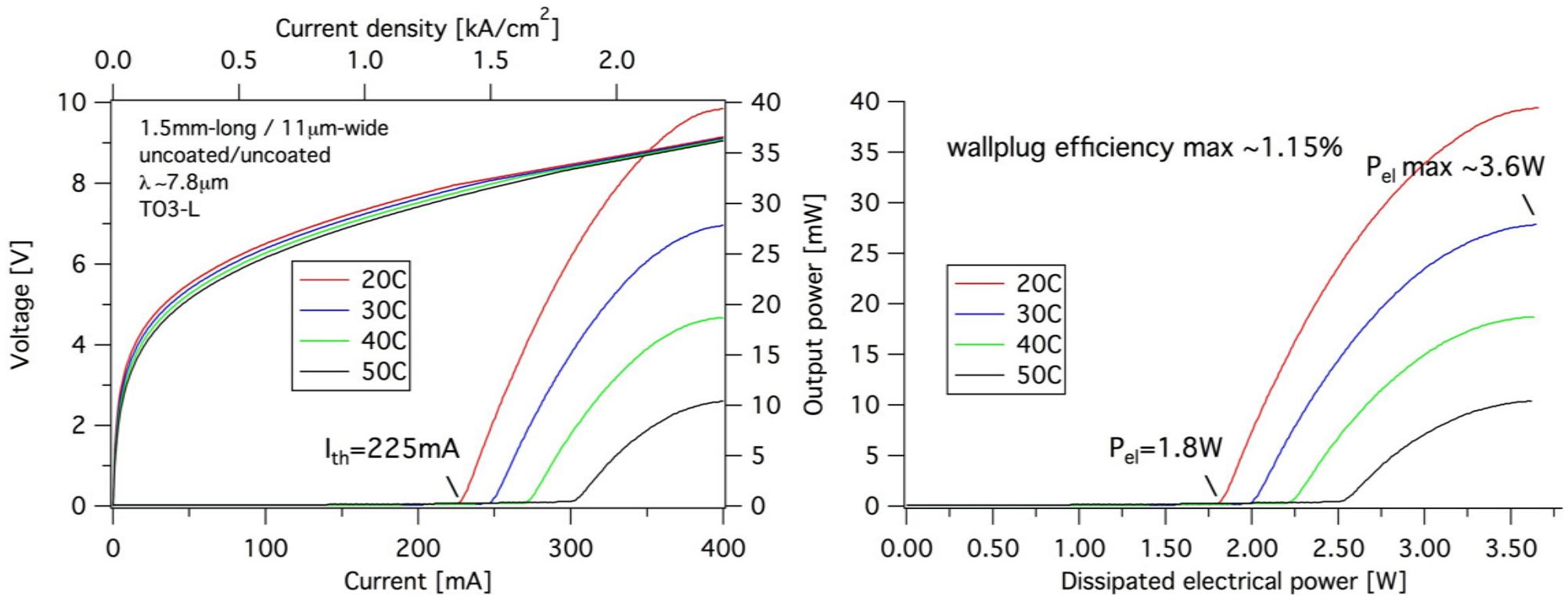


Can we package this devices in low-dissipation packages?

DFB devices at 7.8 μm in TO3-L (dissipation level)

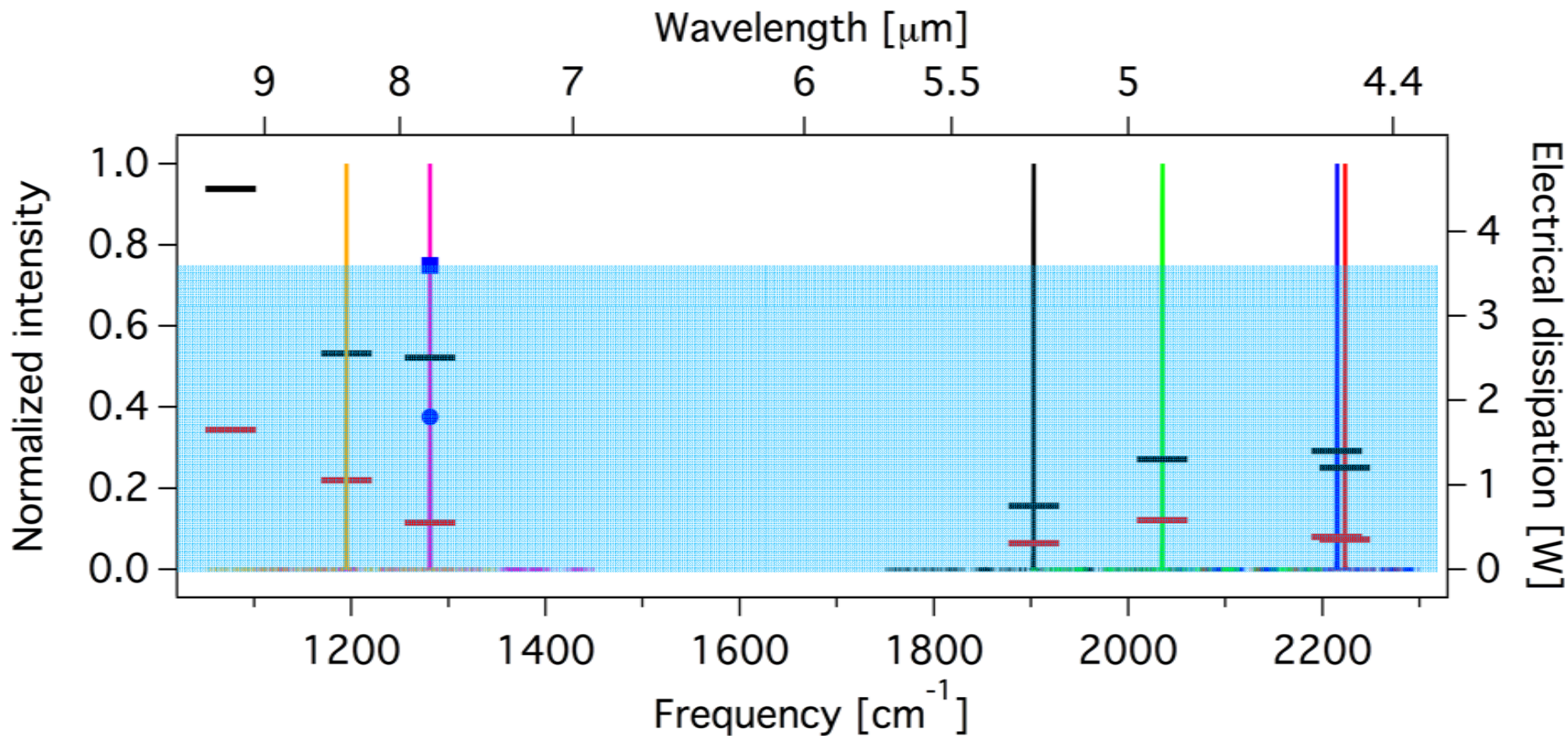


.blue : uncoated device in a TO3-L

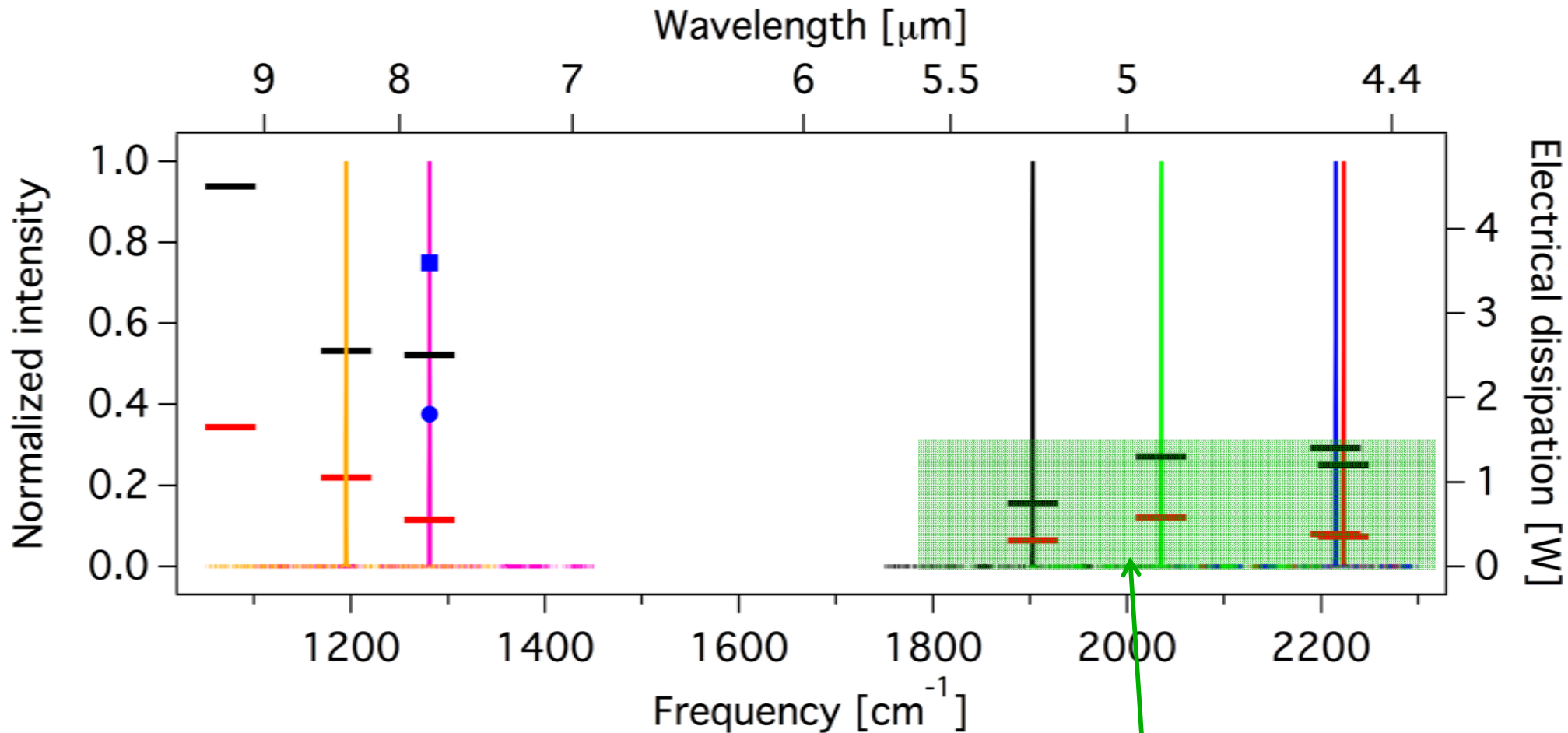


符 higher currents but CW operation
in TO3-L

符 max electrical power : up to 3.6W

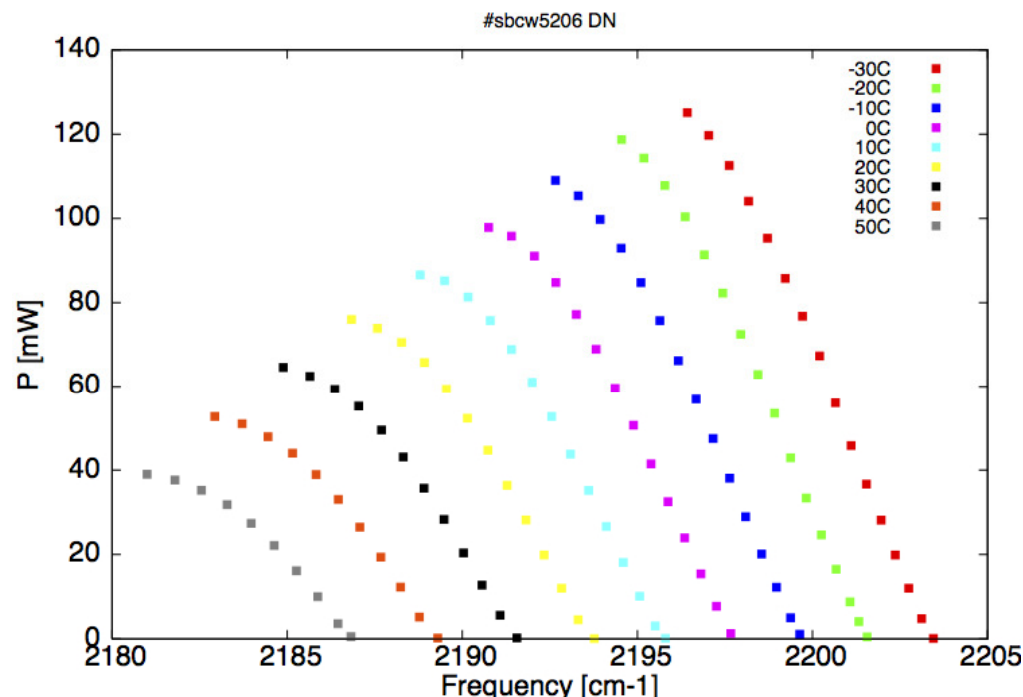
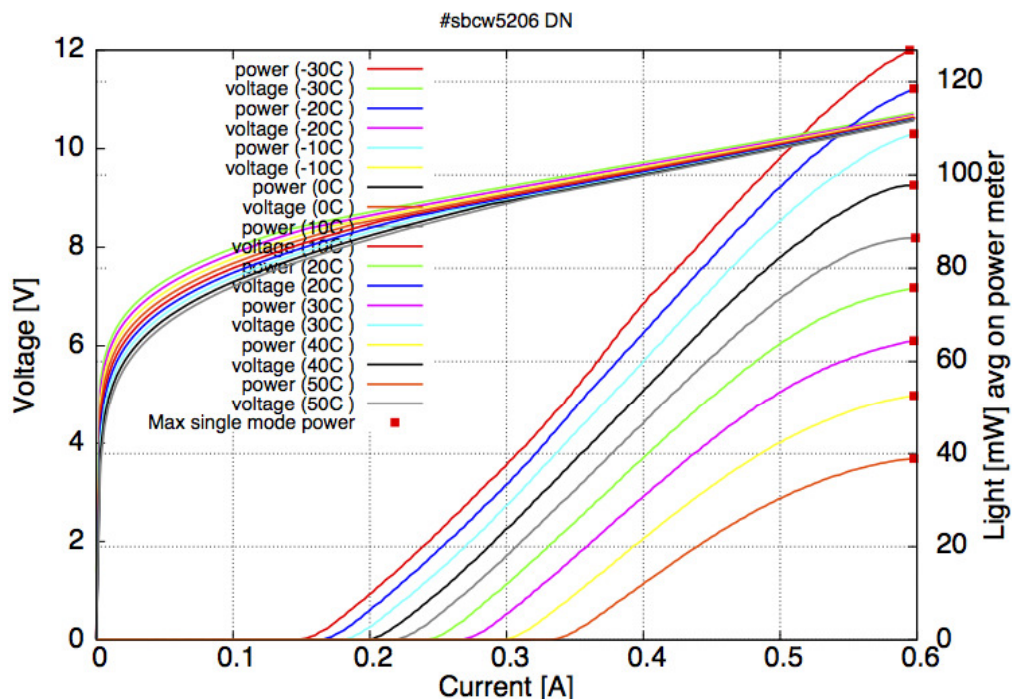


blue : uncoated device in a TO3-L



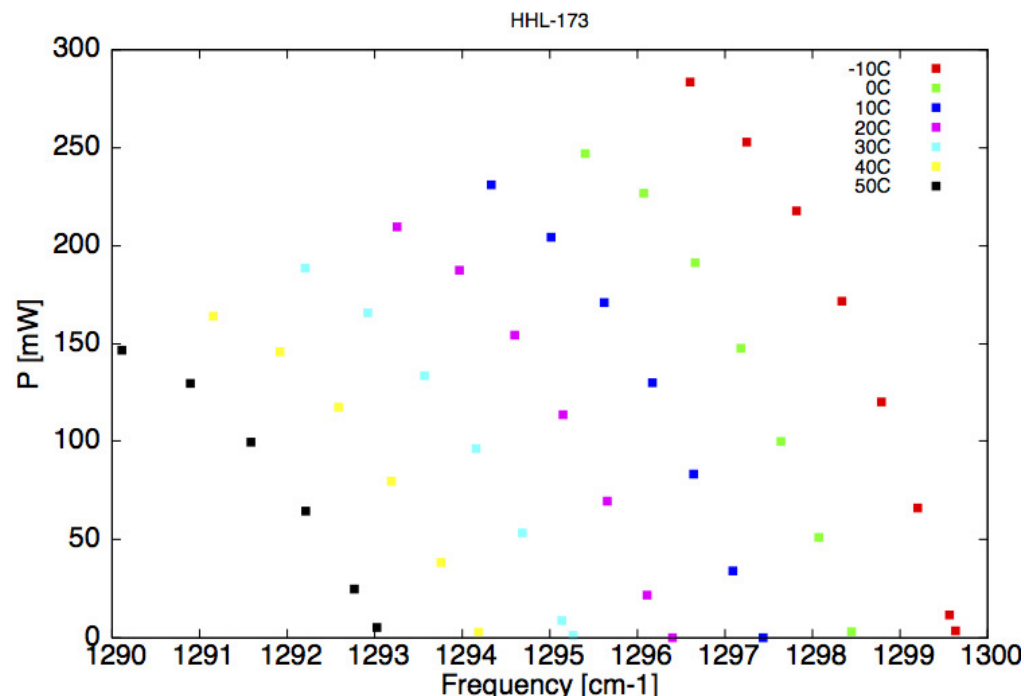
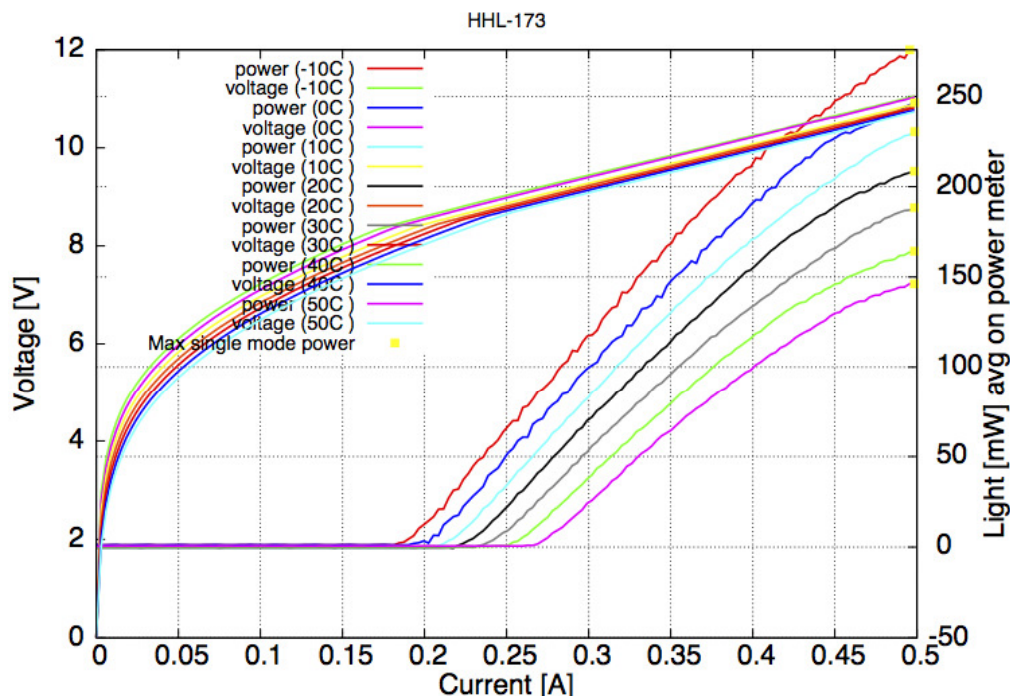
Smaller packages are being investigated

High-power device at 4.56 μm



- ~ 80mW/facet at RT / still > 40mW/facet at 50C
- P_{el} max < 6.4W
- Single mode across the full range

High-power device at 7.72 μm



- ~ 200mW at RT / still **>140mW at 50C**
- P_{el} max < 5.5W
- Single mode across the full range

Conclusion and next steps

- Low-dissipation DFB lasers between 4.5 and 9.3 μm with T_{op} up to $>50\text{C}$
- High-power DFB using the same fabrication process (140mW at 50C episcide-up)
- Soon to be expanded from 3.3 μm to 14 μm
- Genetic optimisation of the active region design to increase the efficiency
- Broad gain optimisation for cw operation
- Cloud simulation capability

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Thank you for your attention

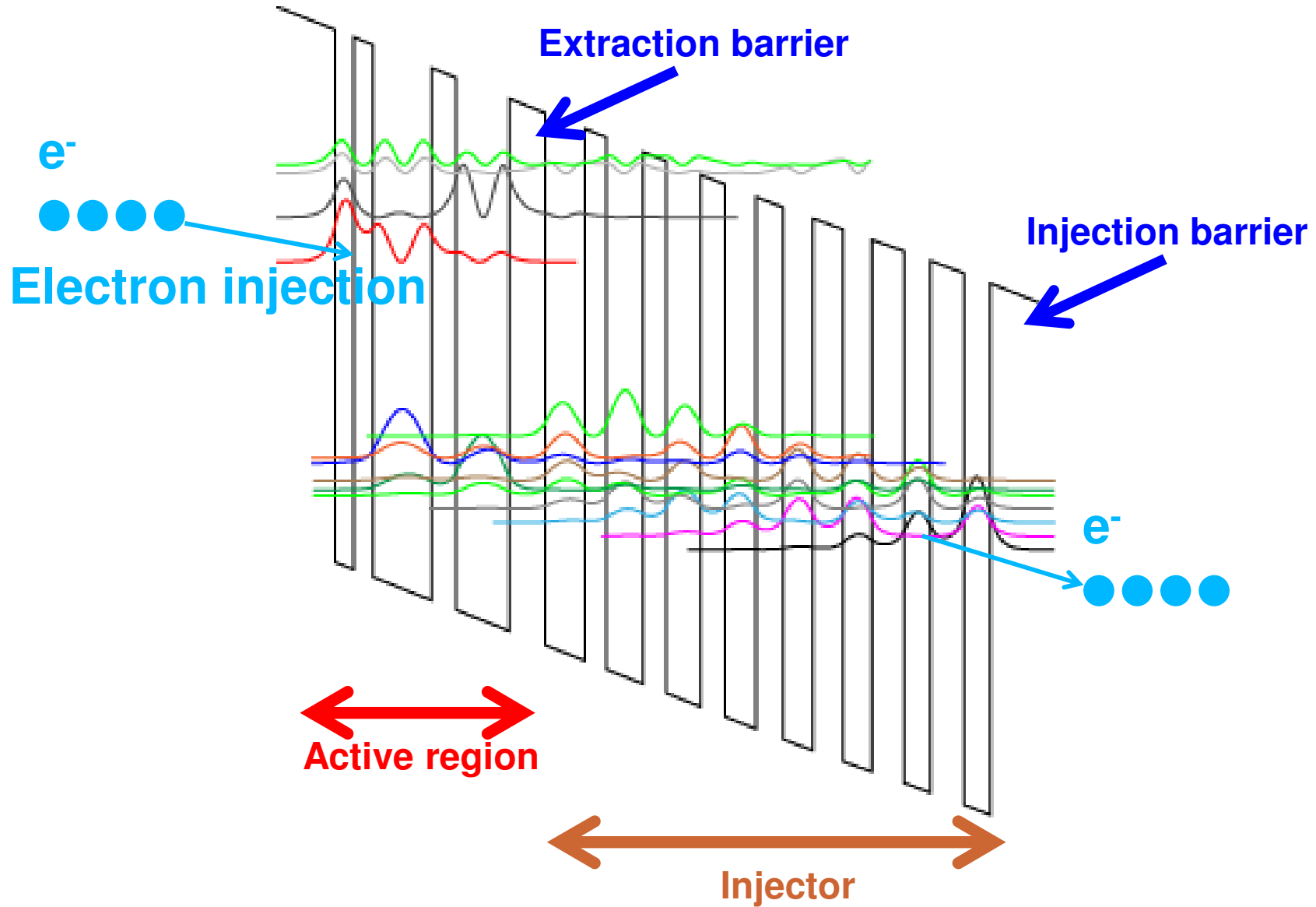
How to improve QCLs?

Better wallplug efficiency, higher powers, broader gain

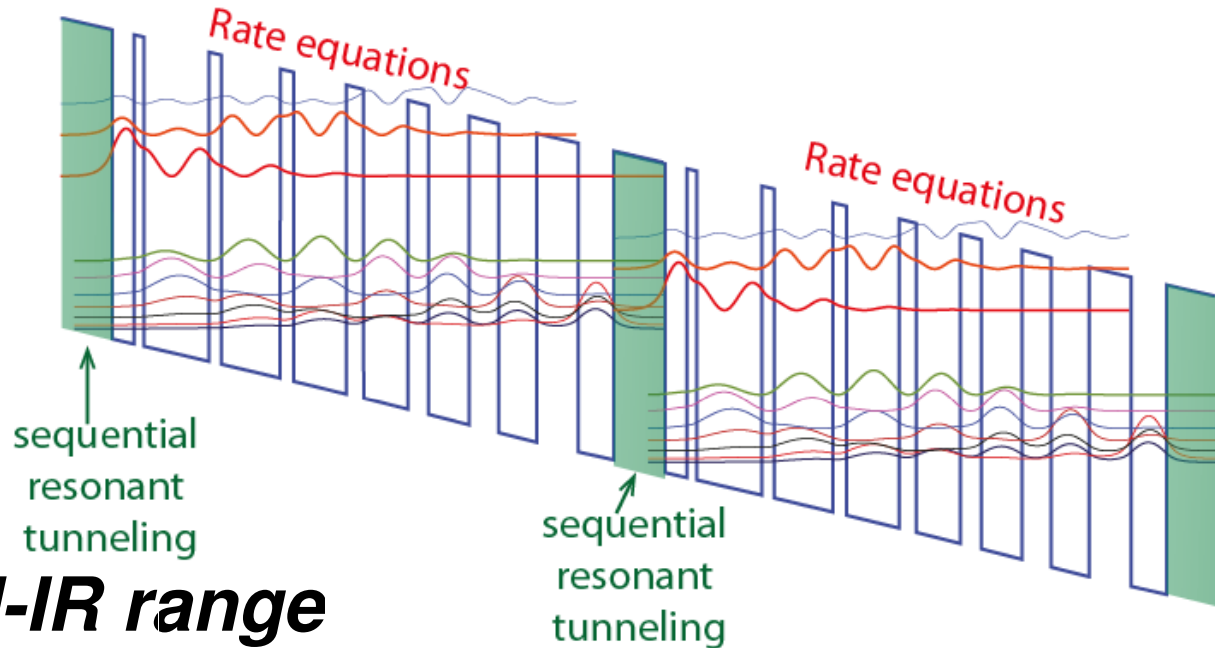
- Technology
- Growth and processing
- Design
 - Local optimization yields contradictory results
 - Try and error very expensive

Reliable simulation tool

QCL design



Density matrix formalism



Reliable in the whole Mid-IR range

**Able to predict optical
power-current-voltage curves**

¹ H. Willenberg et al., Phys. Rev. B. 67, 085315 (2003)

² R. Terazzi et al., New J. Phys. 12, 033045 (2010)

The scattering mechanisms implemented in the computation

- LO-Phonons
- Interface roughness
- Alloy disorder
- Ionized impurities
(Dopants)

Missing interactions:

- Electron-electron
- LA-Phonon

Program input parameters

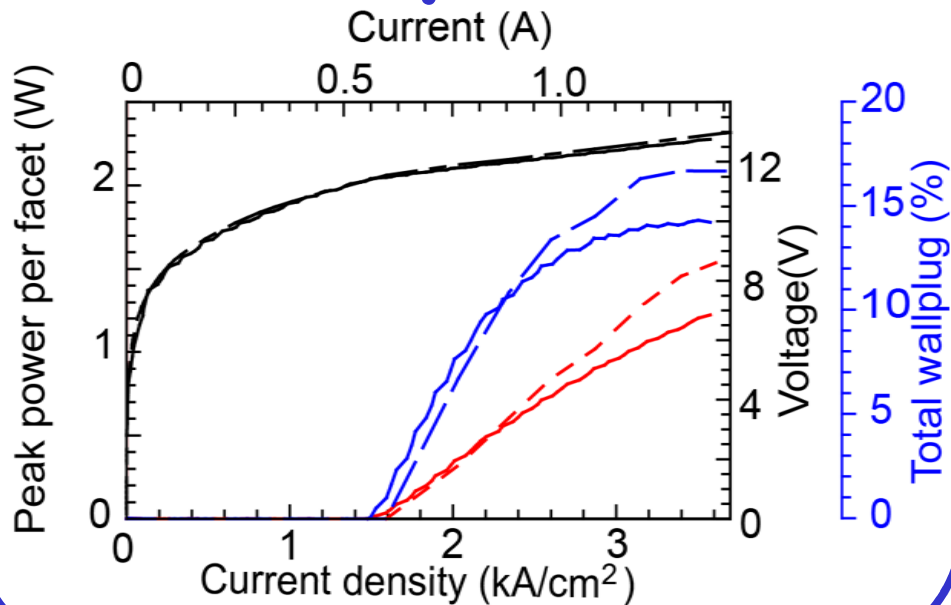
waveguide losses

laser length

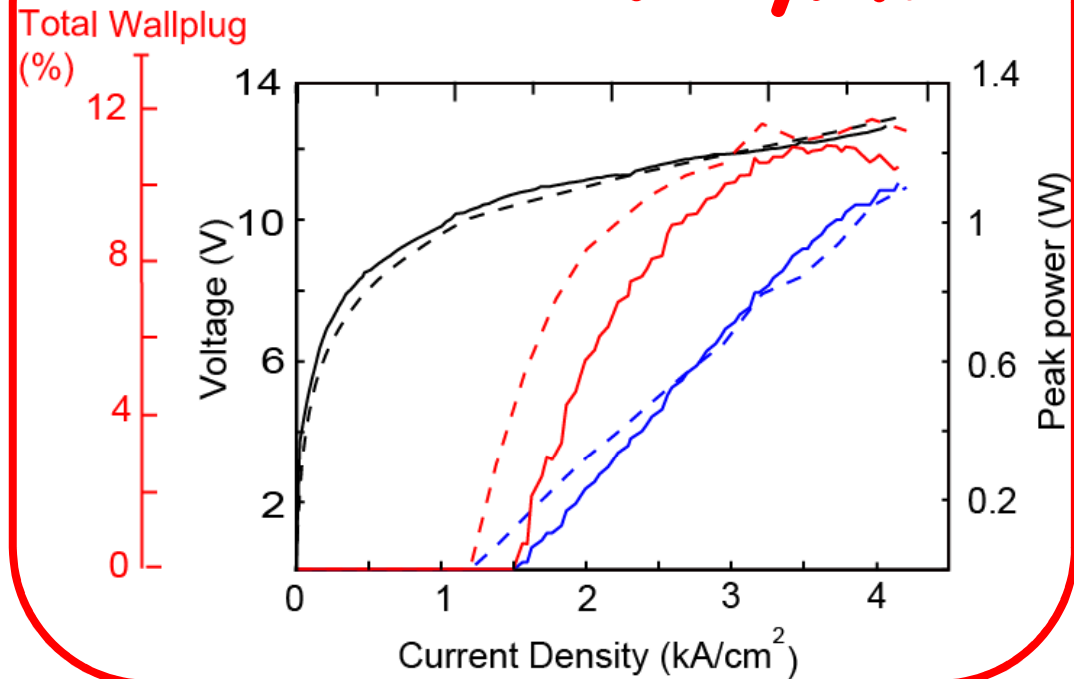
laser width

¹ Unuma et al., J. Appl. Phys. 93, 1586 (2003)

$\lambda = 4.5 \mu\text{m}^*$



$\lambda = 8.5 \mu\text{m}^{**}$



Reliable across the whole Mid-IR range (4-10 μm)

In the 3-4 μm range intervalley scattering missing

* A. Bismuto et al., Appl. Phys. Lett. 98, 091105 (2011)

** A. Bismuto et al., Appl. Phys. Lett. 96, 141105 (2010)

Simulation tool able to predict actual laser performance

Too many parameters to control manually (~20 layers)

Use of genetic algorithms (fully automatized)

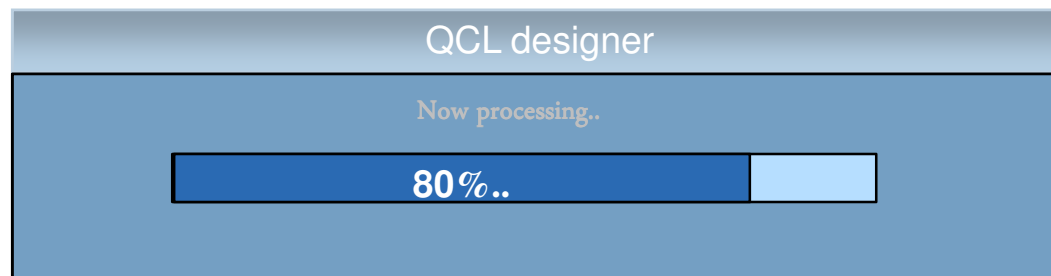


Merit function selection

Wallplug efficiency

Use of ETH Cluster (BRUTUS, 10000 cores)

Currently using Amazon cloud service

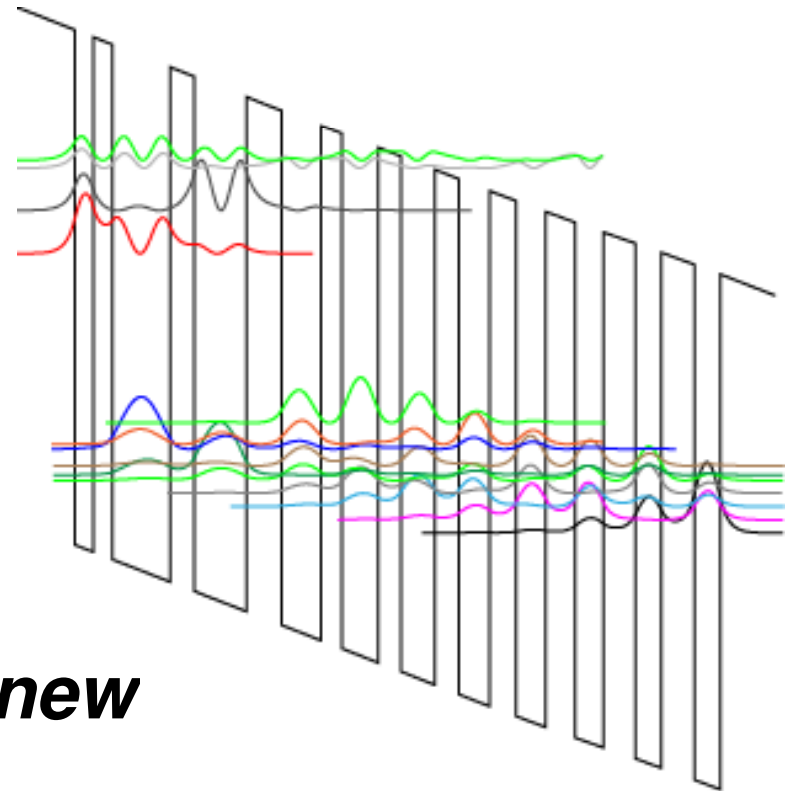


Starting point: Bound to continuum design at 4.6 μm

Q. Yang et Al., Appl. Phys. Lett. 93, 251110 (2008)

Random variation of the reference design
(less than 20%)

Best designs used to create the new
population (*Darwin's law*)

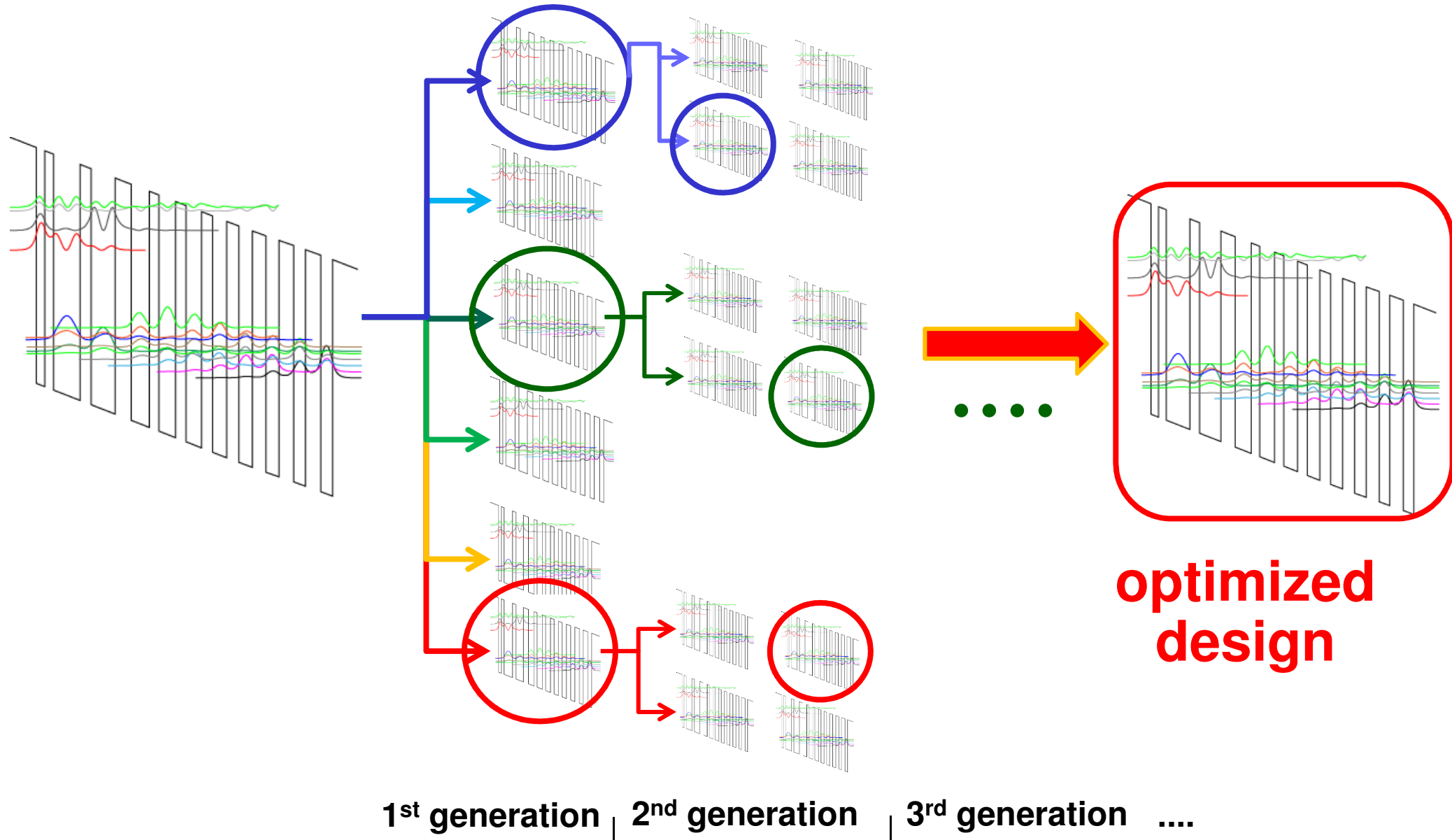


33000 individuals per population

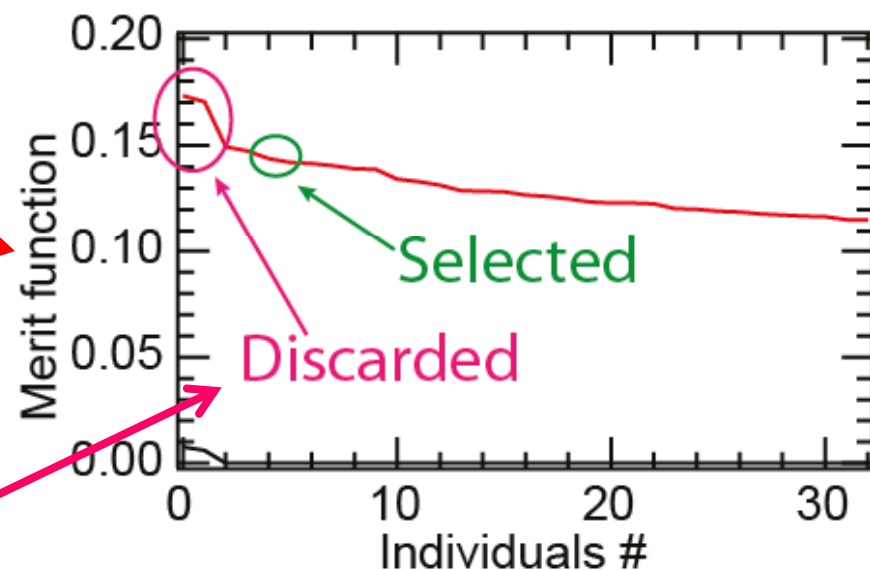
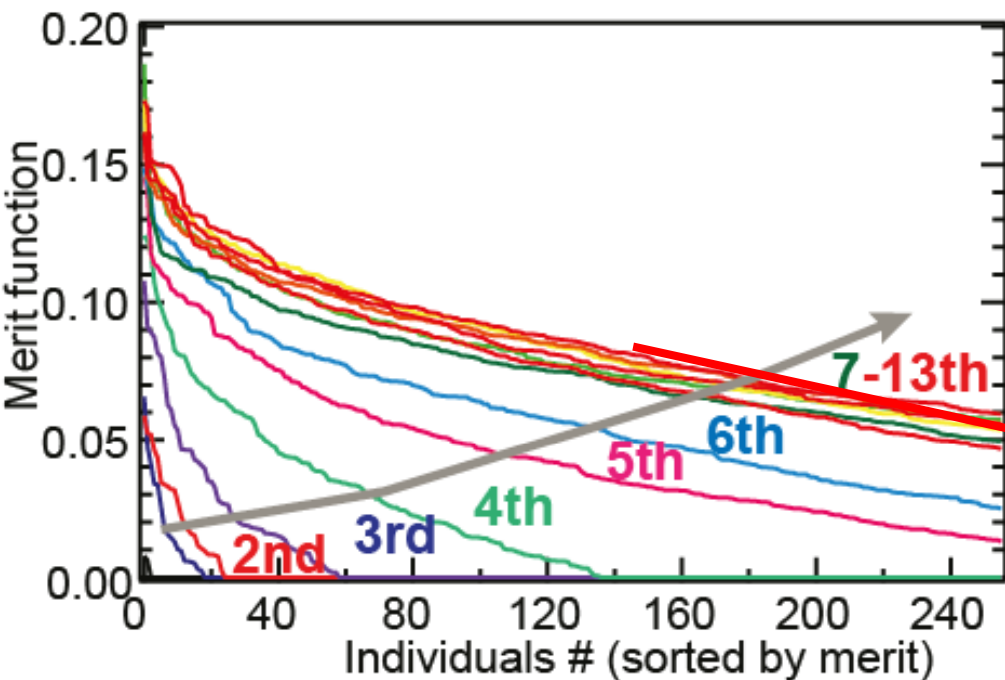
32 designs selected to create the new generation

A. Bismuto et al., APL 101, 021103 (2012)

Toward genetic optimization



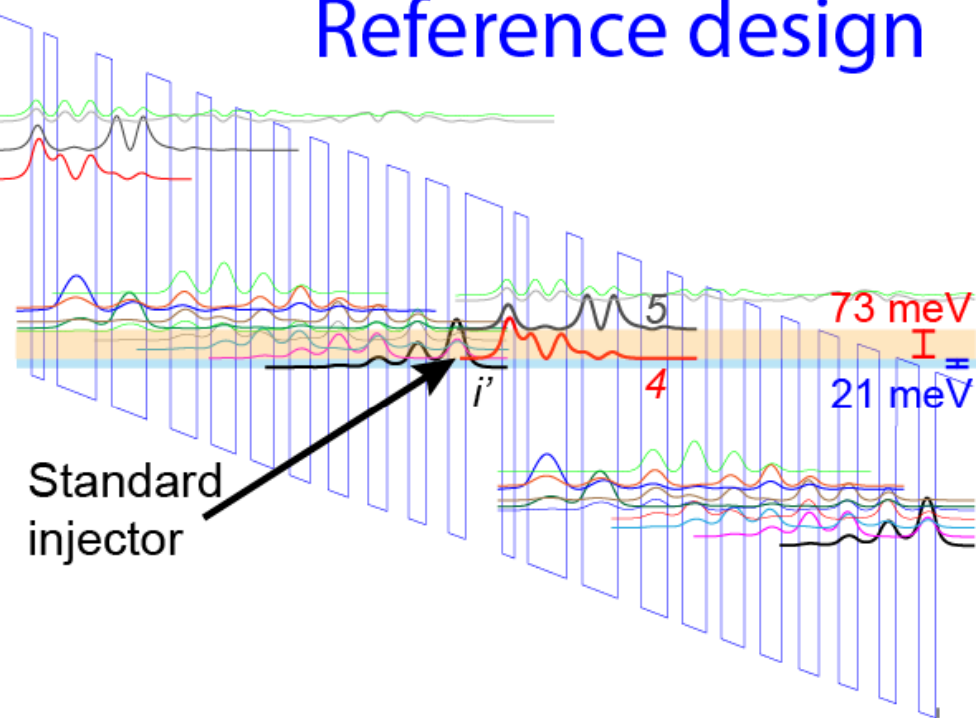
Merit function: Wallplug efficiency



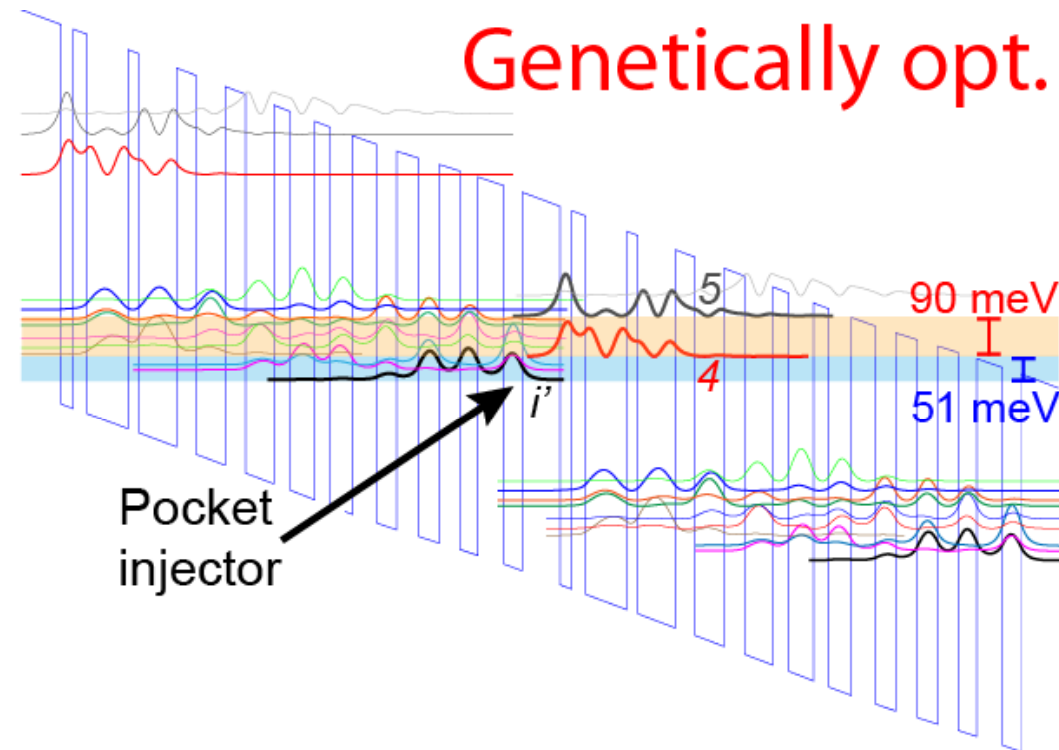
Unstable pathological structures were excluded (e.g. coherent transport of electrons over unphysical lengths)

Structure in the average position of the best generation selected

Reference design



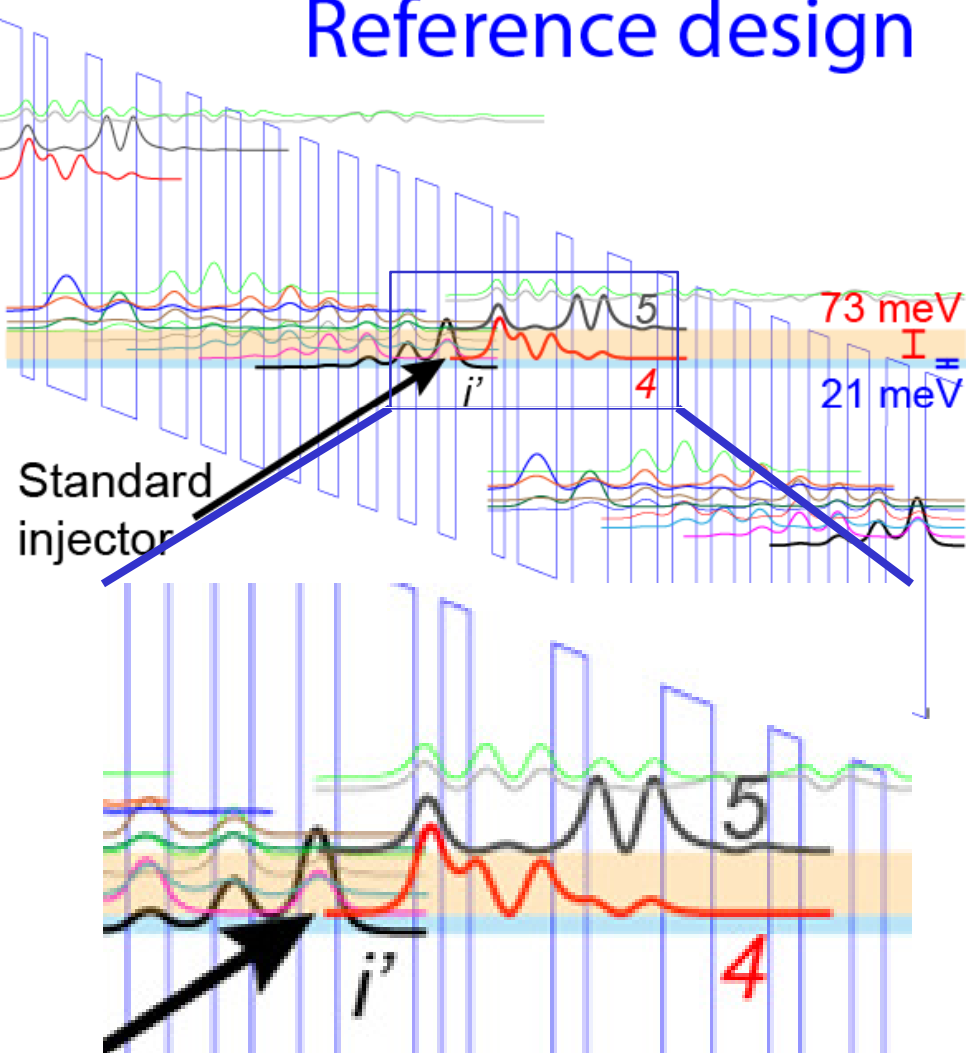
Genetically opt.



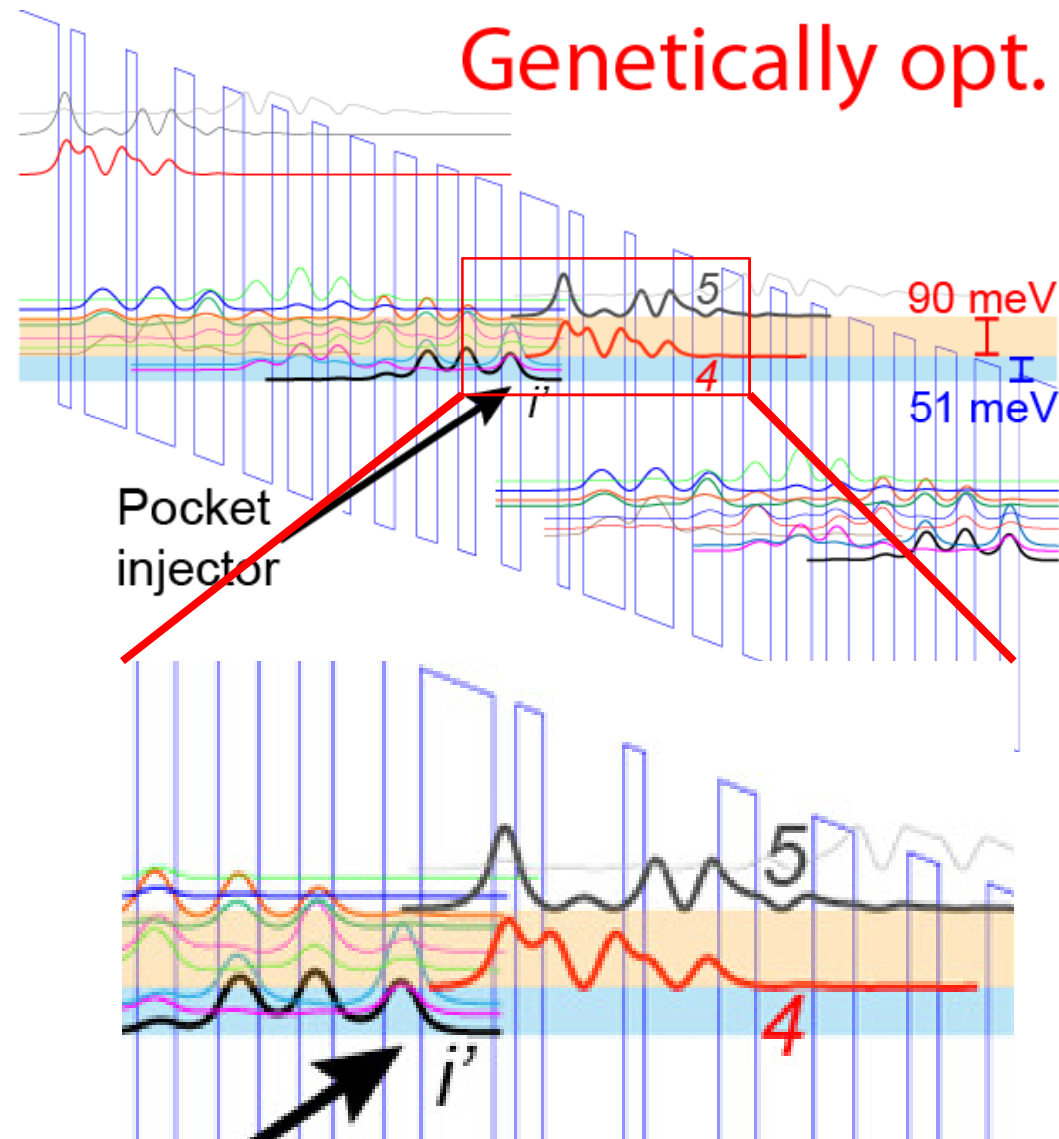
Emission wavelength kept constant

Lower alignment voltage, higher gain

Reference design



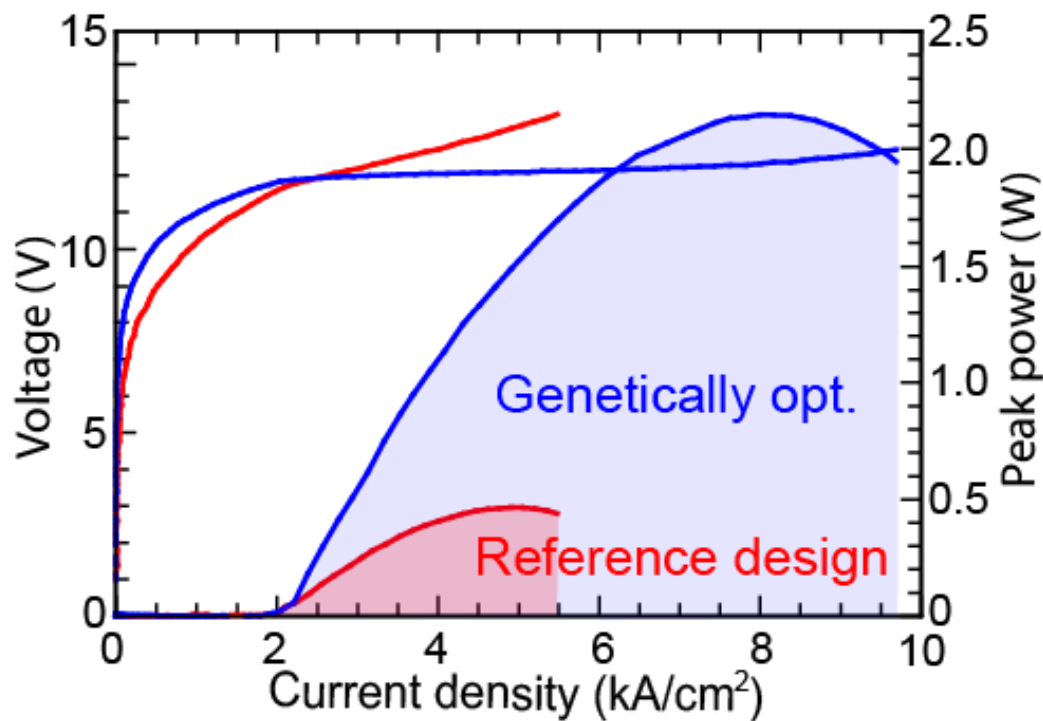
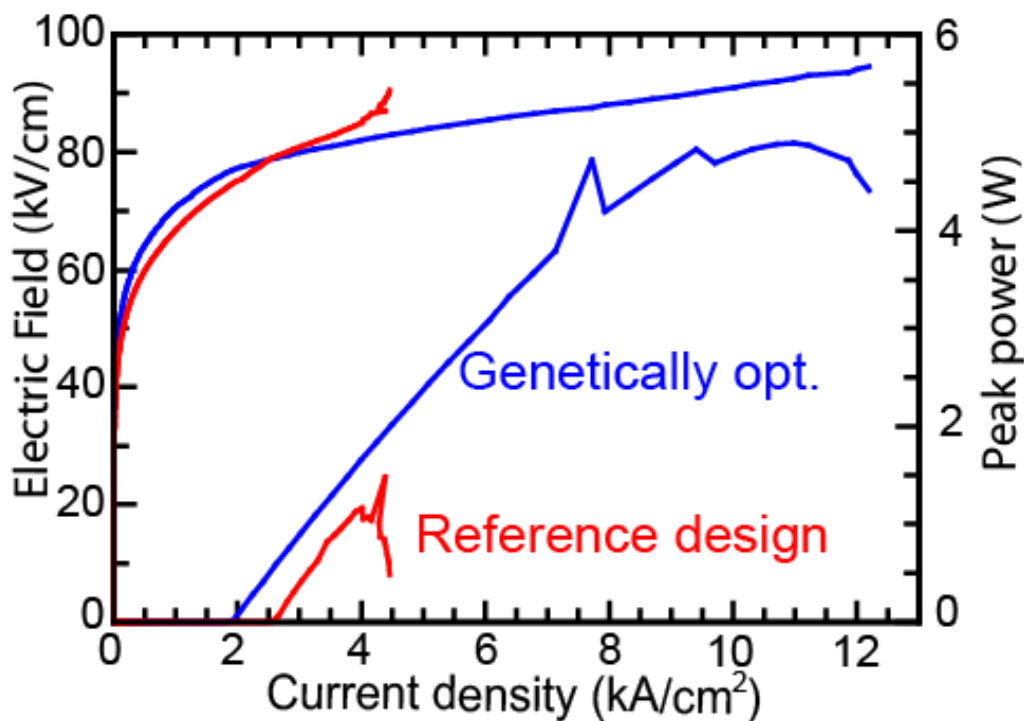
Genetically opt.



ALPES
LASERS

Simulations

Measurements



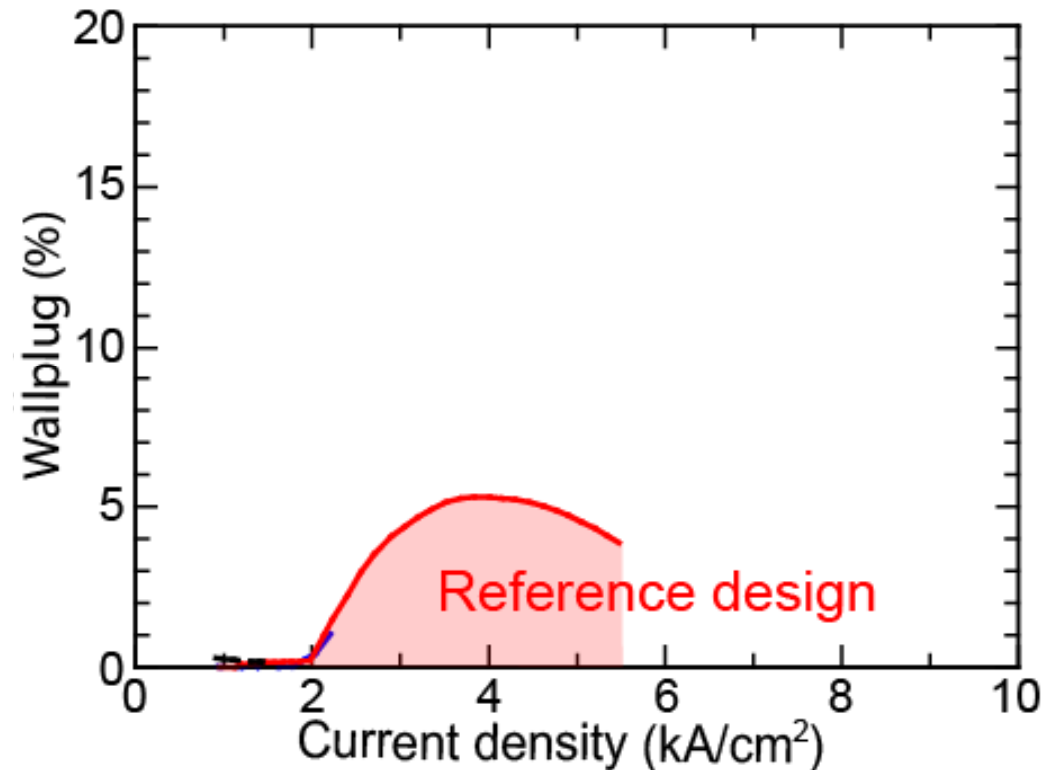
8.5 μm wide, 4.9 mm long laser

Lower alignment voltage

Higher power

Smaller threshold

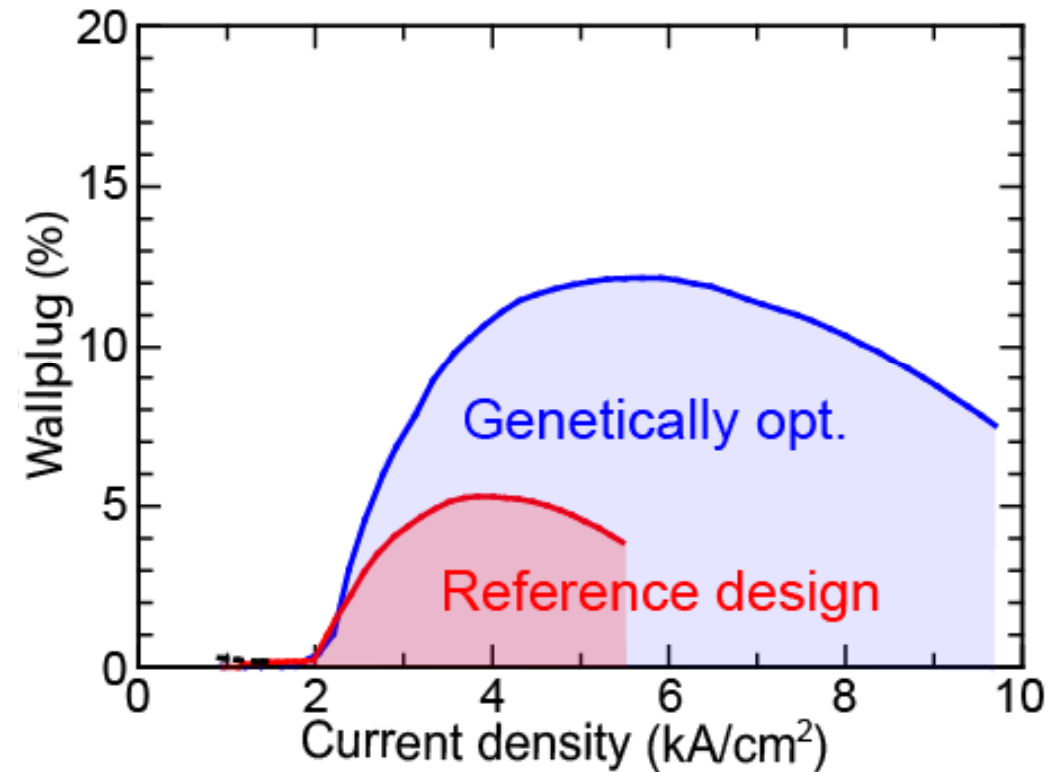
The optimized design shows higher efficiency



**growth optimization has to be performed
also on the optimized design**

A. Bismuto et al., APL 101, 021103 (2012)

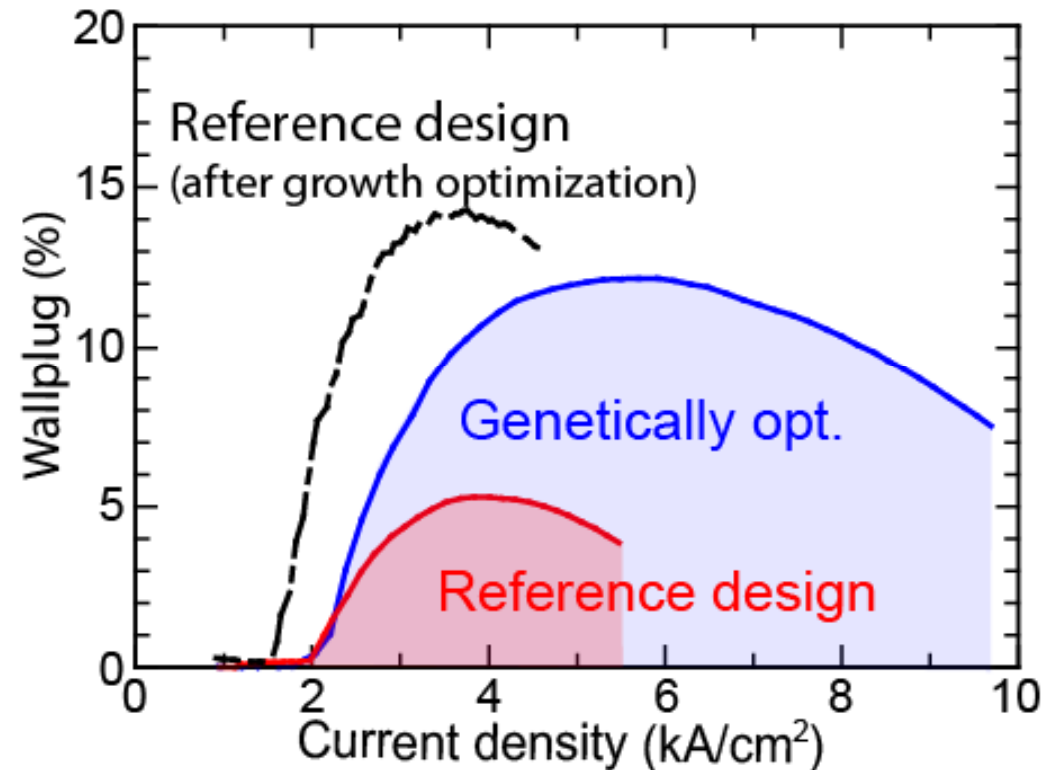
The optimized design shows higher efficiency



**growth optimization has to be performed
also on the optimized design**

A. Bismuto et al., APL 101, 021103 (2012)

The optimized design shows higher efficiency



growth optimization as to be performed
also on the optimized design

The scattering mechanisms implemented in the computation

○ LO-Phonons

○ Interface roughness

○ Alloy disorder

○ Ionized impurities
(Dopants)

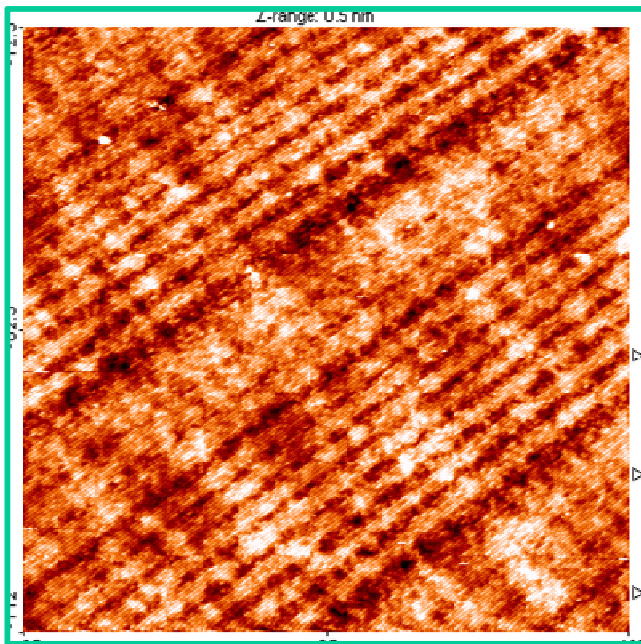


**Interface roughness has
a major impact on laser
performance**

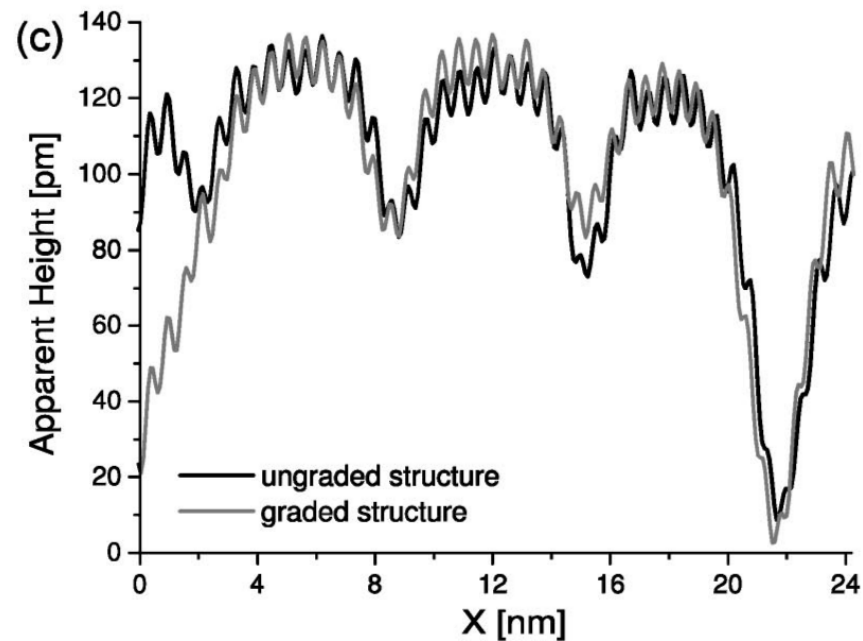
How to improve the quality of the interfaces...

¹ Unuma et al., J. Appl. Phys. 93, 1586 (2003)

STM cross-section



Cut across interfaces



- Interfaces are
- graded (over 3-4ML)
 - rough

P. Offerman et al., Appl. Phys. Lett. 83, 4131 (2003)

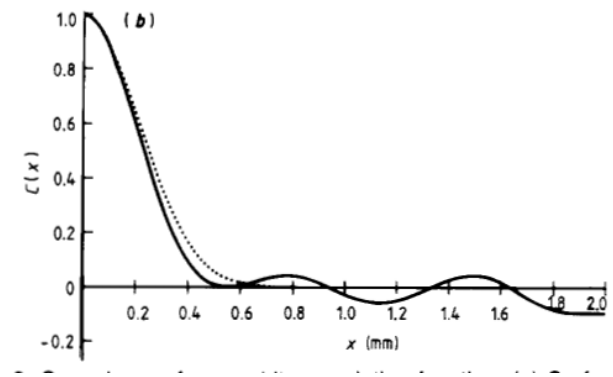
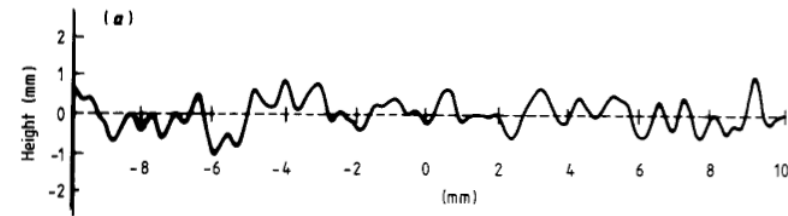
ALPES LASERS Interface roughness

Most relevant scattering mechanism in mid-IR quantum cascade lasers

$$\langle \Delta(r) \Delta(r') \rangle = \Delta^2 \exp\left(-\frac{|r - r'|^2}{\Lambda^2}\right)$$

↑
average step
height

←
correlation
length



- Historically, focused on the minimization of the emission broadening
- Recently high performance broad gain lasers were presented ^{1,2}

..Is emission broadening the right parameter?

¹ A. Bismuto et al., Appl. Phys. Lett. 96, 141105 (2010)

² Y. Yao et al., New J. Phys. 97, 081115 (2010)

³ Unuma et al., J. Appl. Phys. 93, 1586 (2003)

ALPES LASERS

How to modify the correlation length?

Growth temperature \longleftrightarrow Correlation length (Λ)

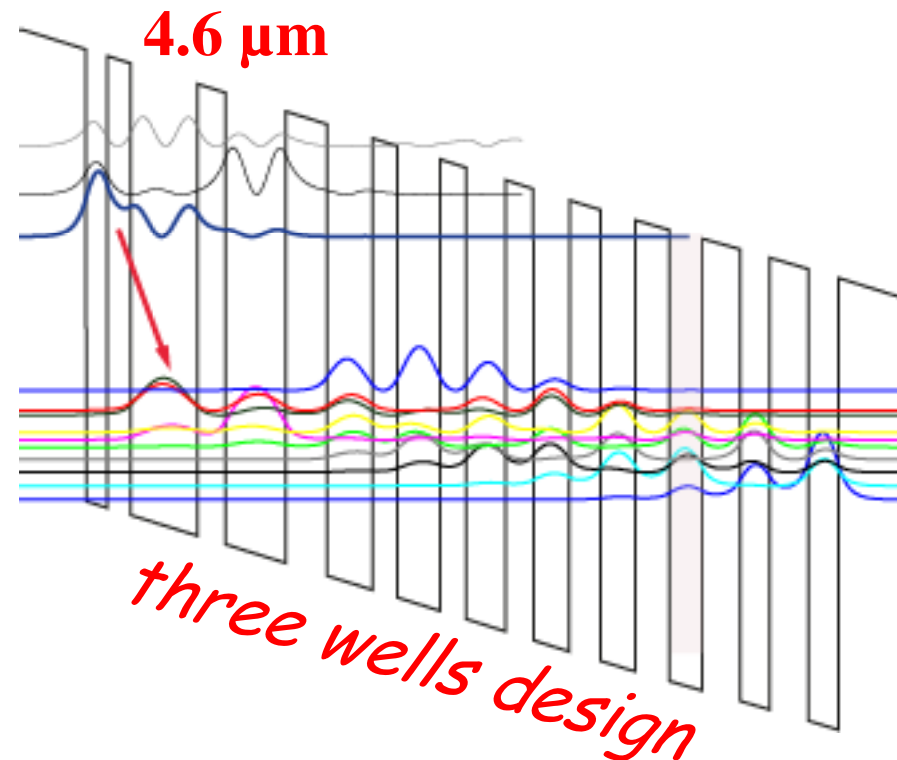
Smaller effect temperature dependence of step height (Δ)

Same processing

$T=475\text{ }^{\circ}\text{C}$

$T=515\text{ }^{\circ}\text{C}$

$T=525\text{ }^{\circ}\text{C}$



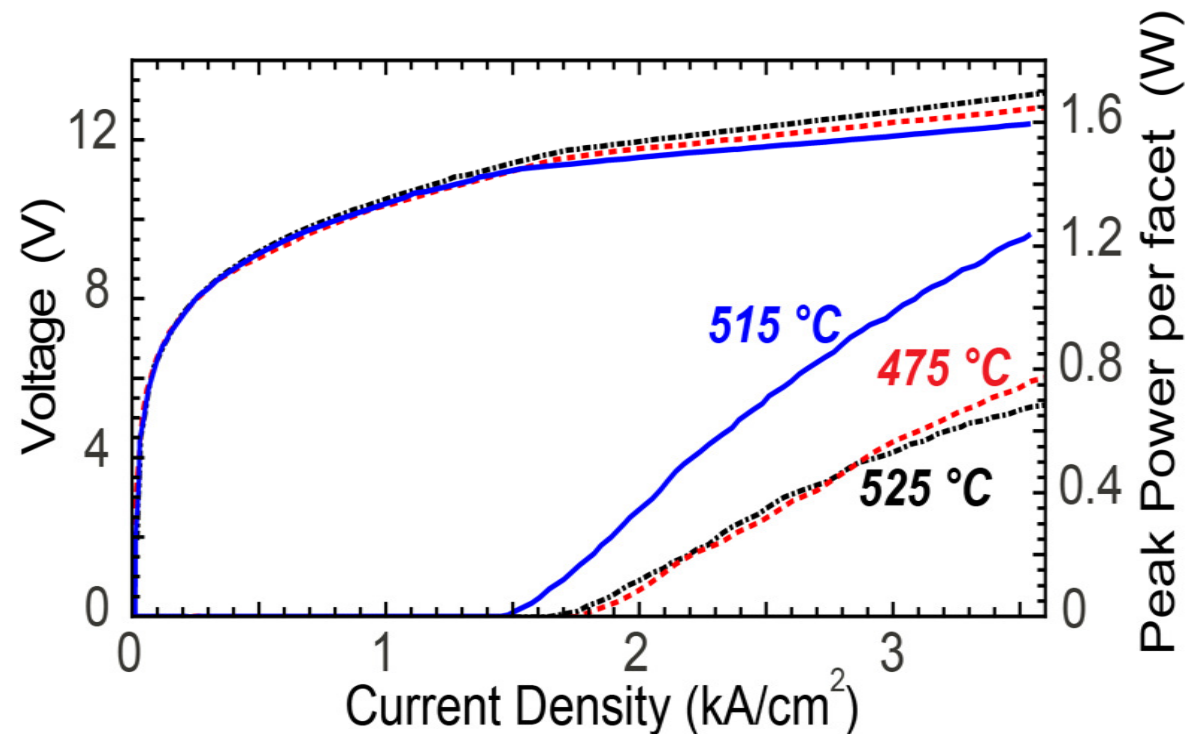
Diagonal design more sensitive to the interface roughness

ALPES LASERS How to modify the correlation length?

Growth temperature \longleftrightarrow Correlation length (Λ)

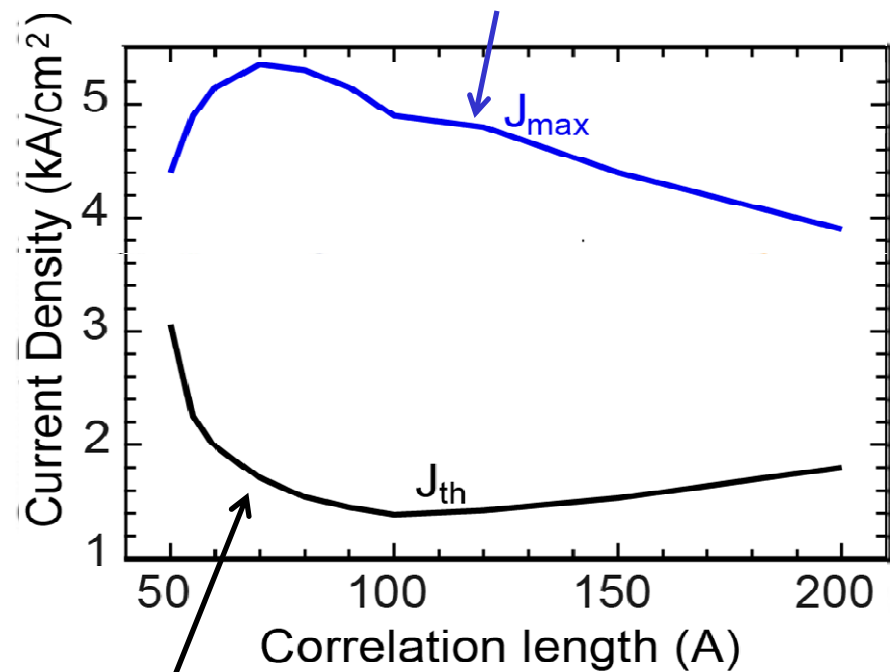
Smaller effect temperature dependence of step height (Δ)

Same processing
T=475 °C
T=515 °C
T=525 °C



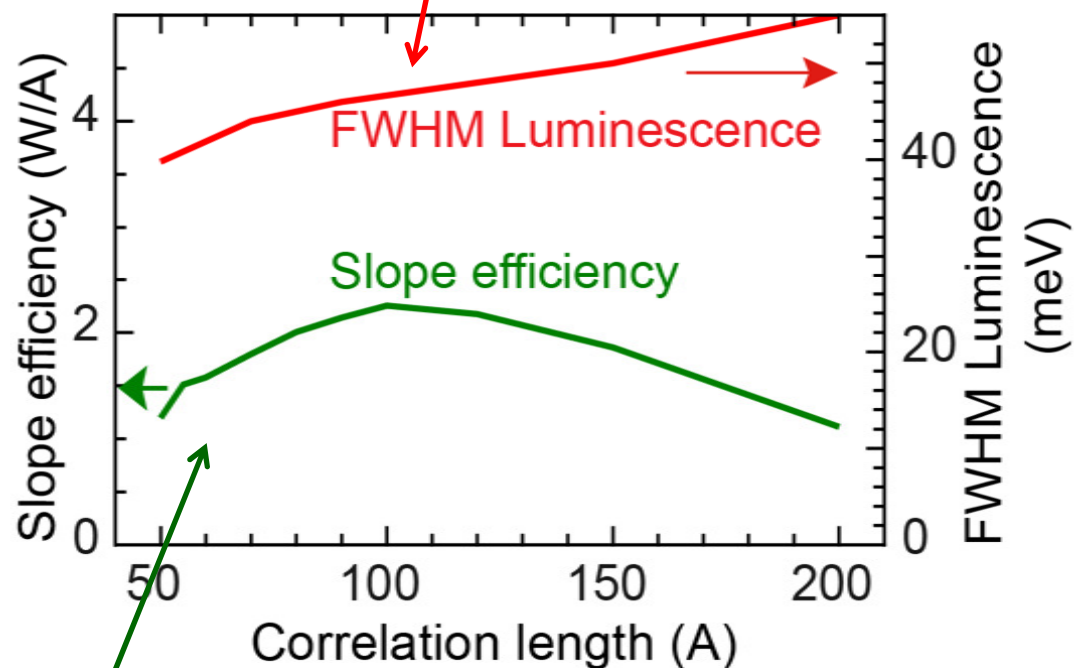
Growth conditions are modified to systematically vary interface roughness

Current at roll-over



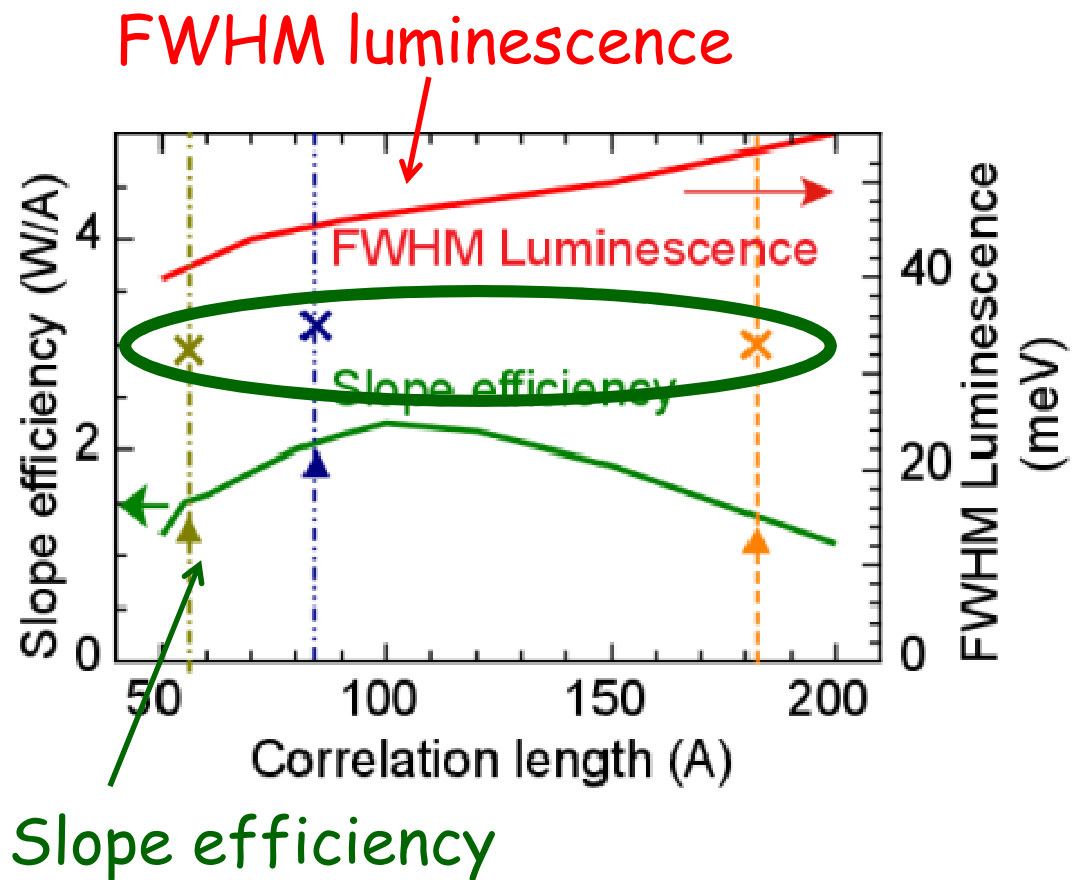
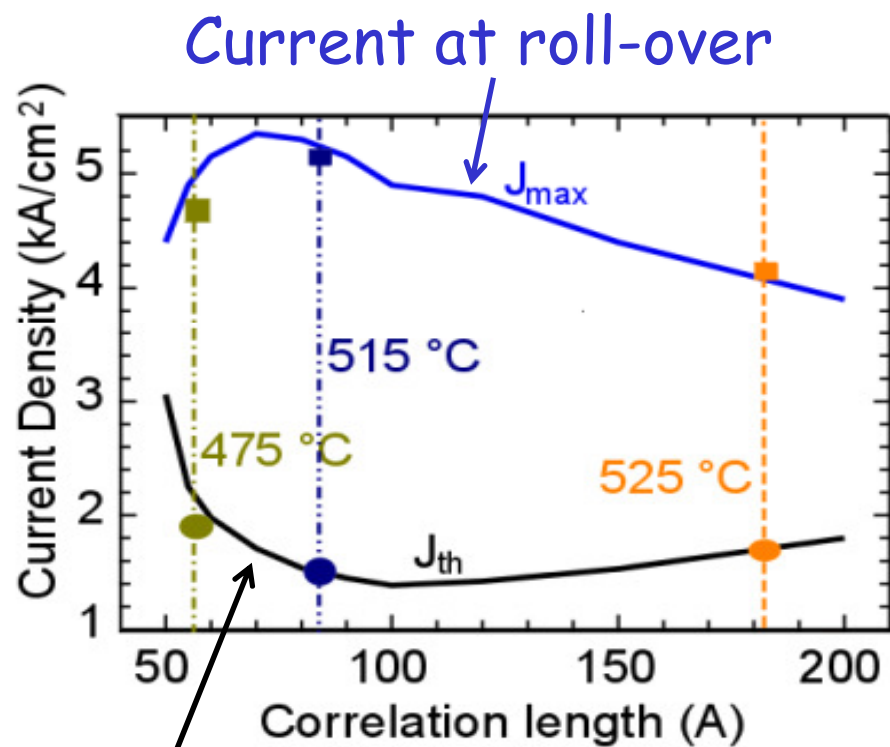
Threshold current density

FWHM luminescence



Slope efficiency

¹ A. Bismuto et al., Appl. Phys. Lett. 98, 091105 (2011)



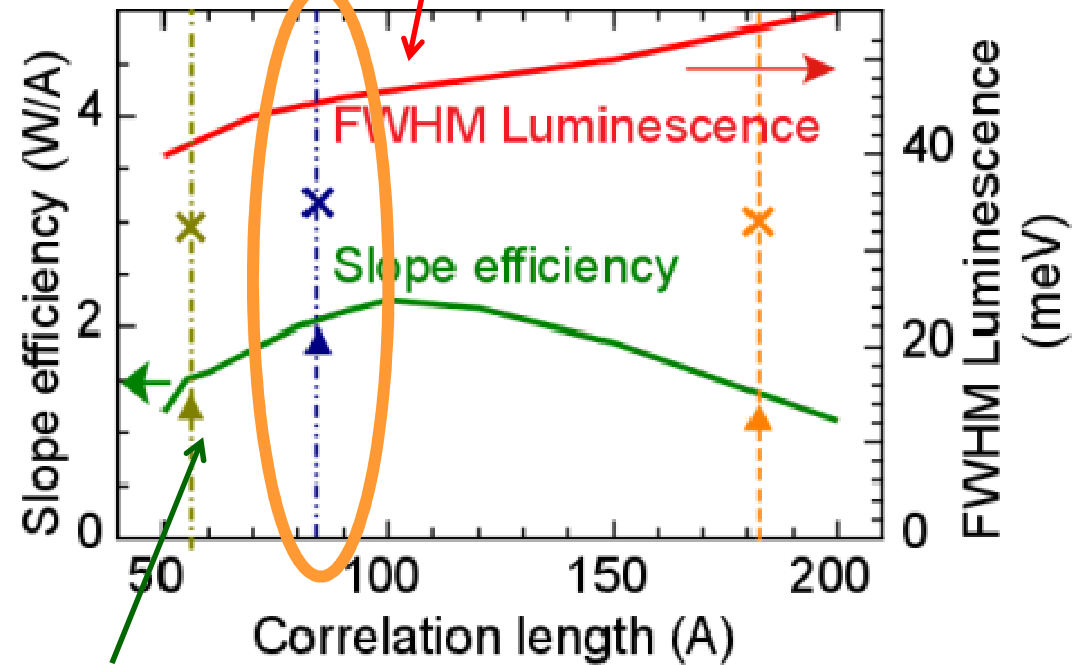
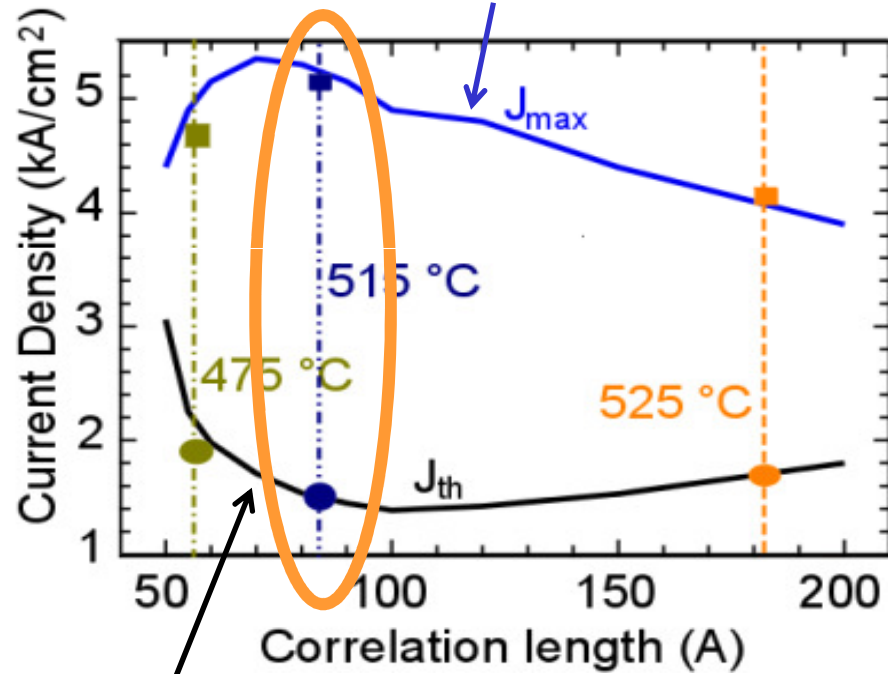
Model fails to predict emission linewidths

¹ A. Bismuto et al., Appl. Phys. Lett. 98, 091105 (2011)

Model fails to predict emission linewidths

FWHM luminescence

Current at roll-over



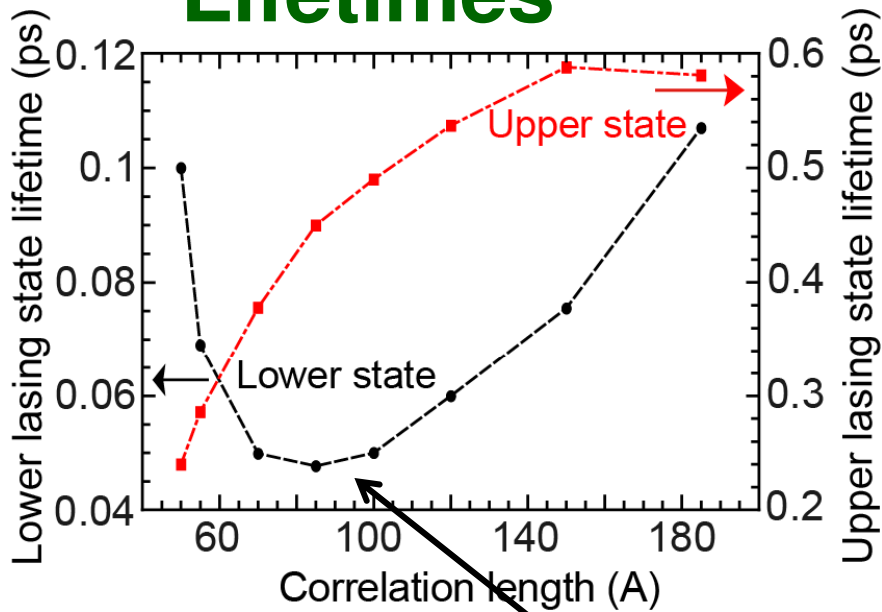
Threshold current density

Best laser performance for $\Lambda \sim 90 \text{ \AA}$

¹ A. Bismuto et al., Appl. Phys. Lett. 98, 091105 (2011)

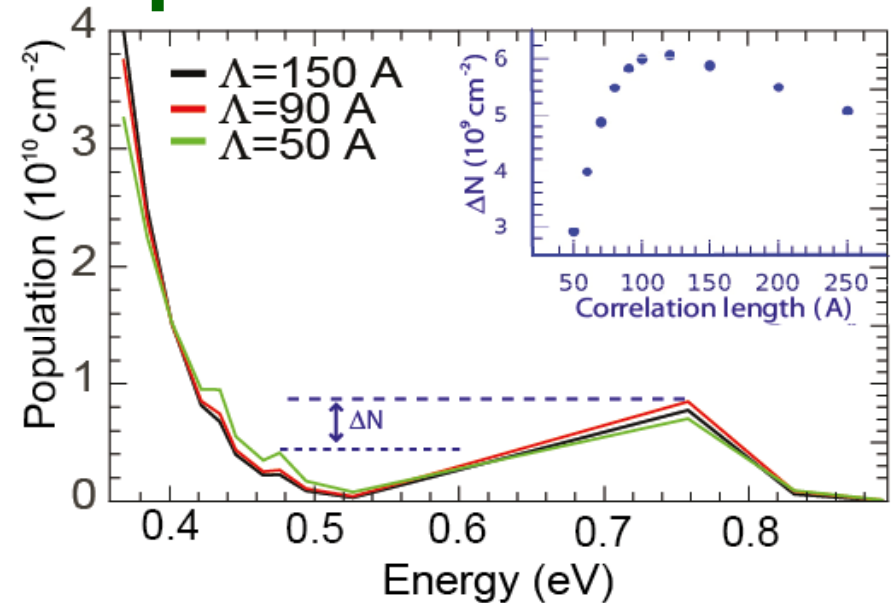
How to justify laser behavior ?

Lifetimes



Lower lasing state shows a minimum
corresponding to best laser performance

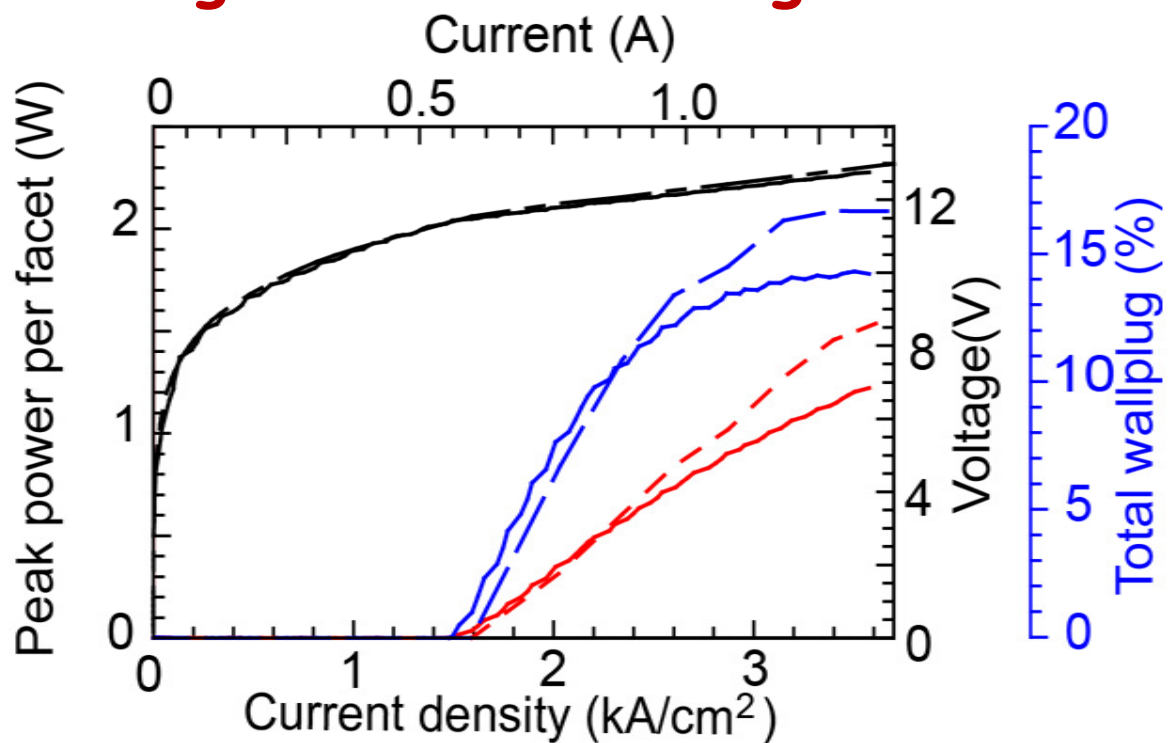
Population inversion



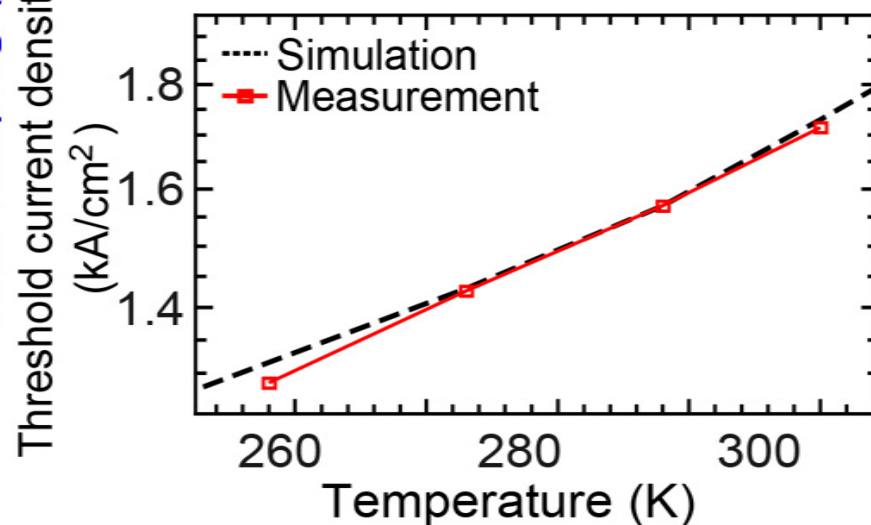
Population inversion
shows a maximum

resonance corresponding to $q\Lambda \sim 1$
(q exchanged wavevector during intersubband transition)
(transition energy of 34 meV)

Light-current-voltage

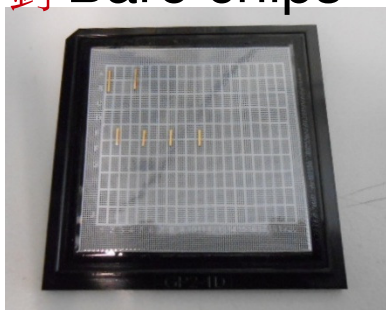


J_{th} vs. Temperature

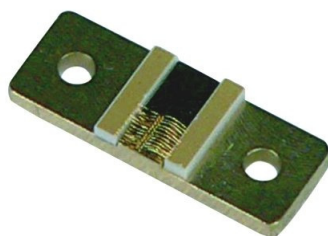


Simulated curves (dashed)
Measured curves

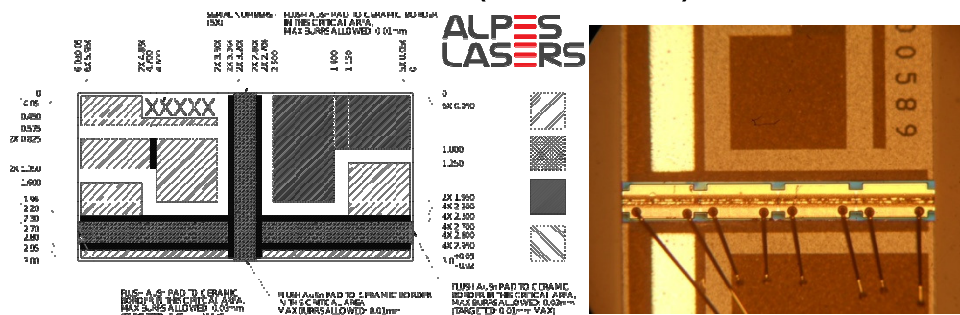
鍍 Bare chips



鍍 NS



鍍 AIN submount (3x6mm)



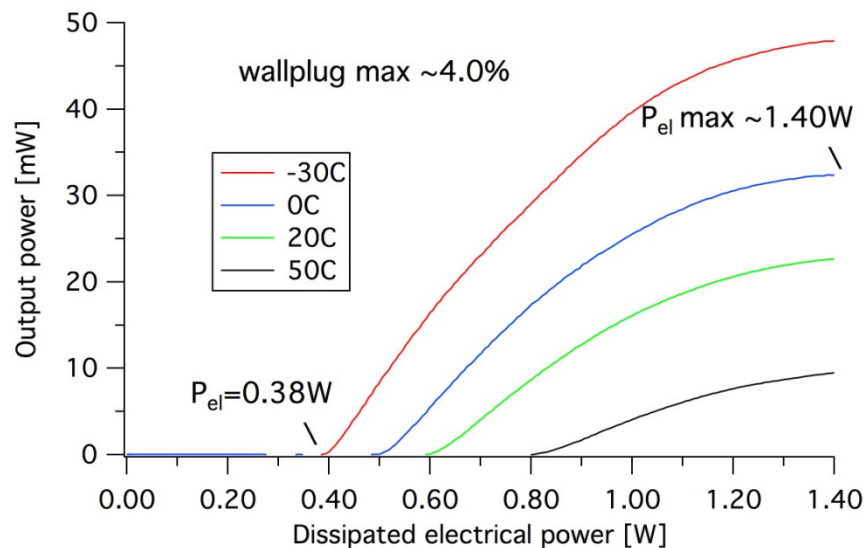
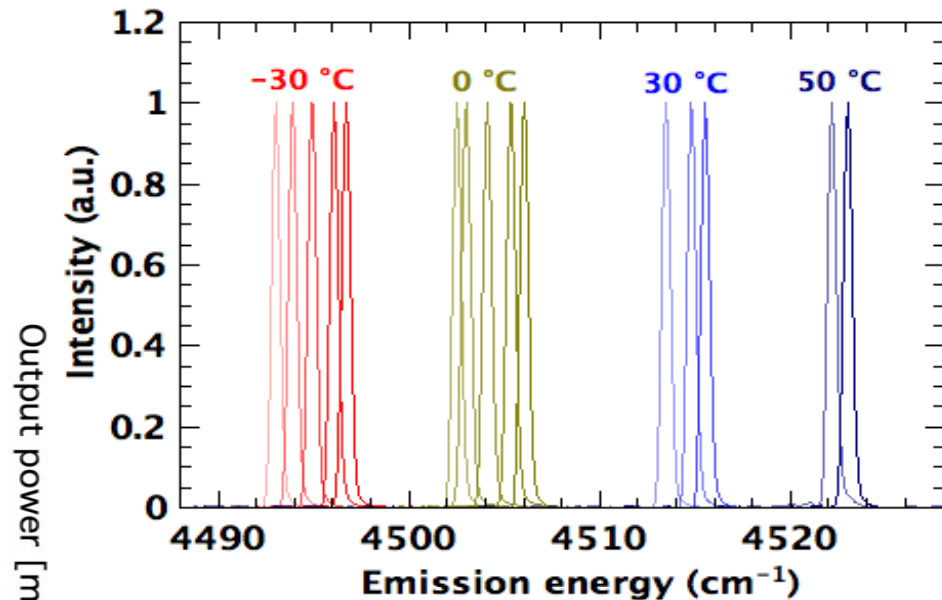
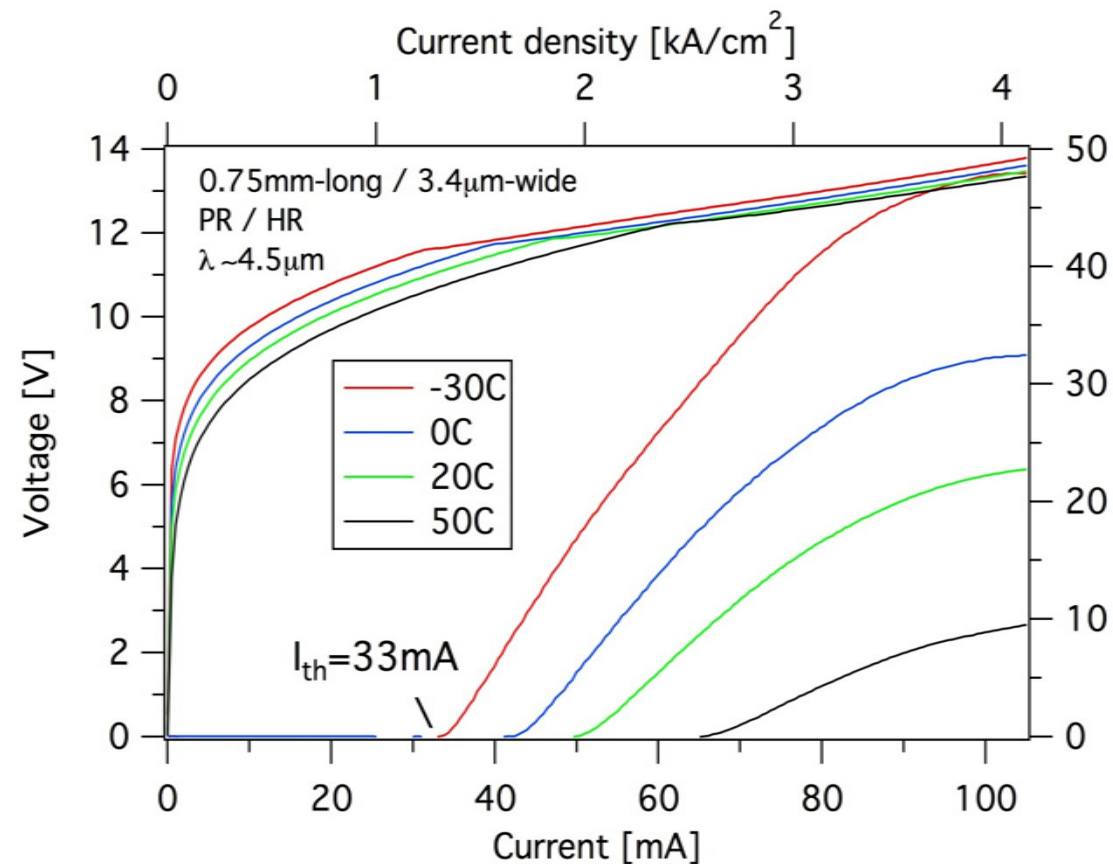
鍍 TC3



鍍 Driver kits

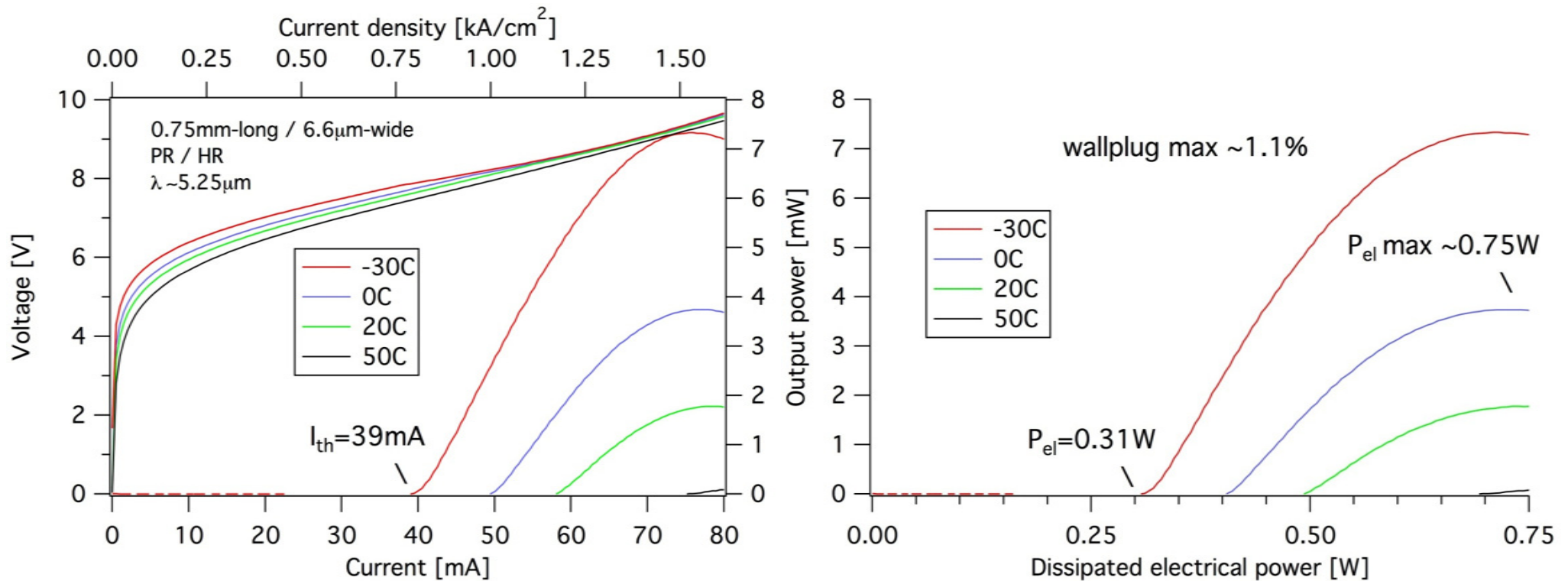


Low-dissipation DFB devices at 4.5 μm



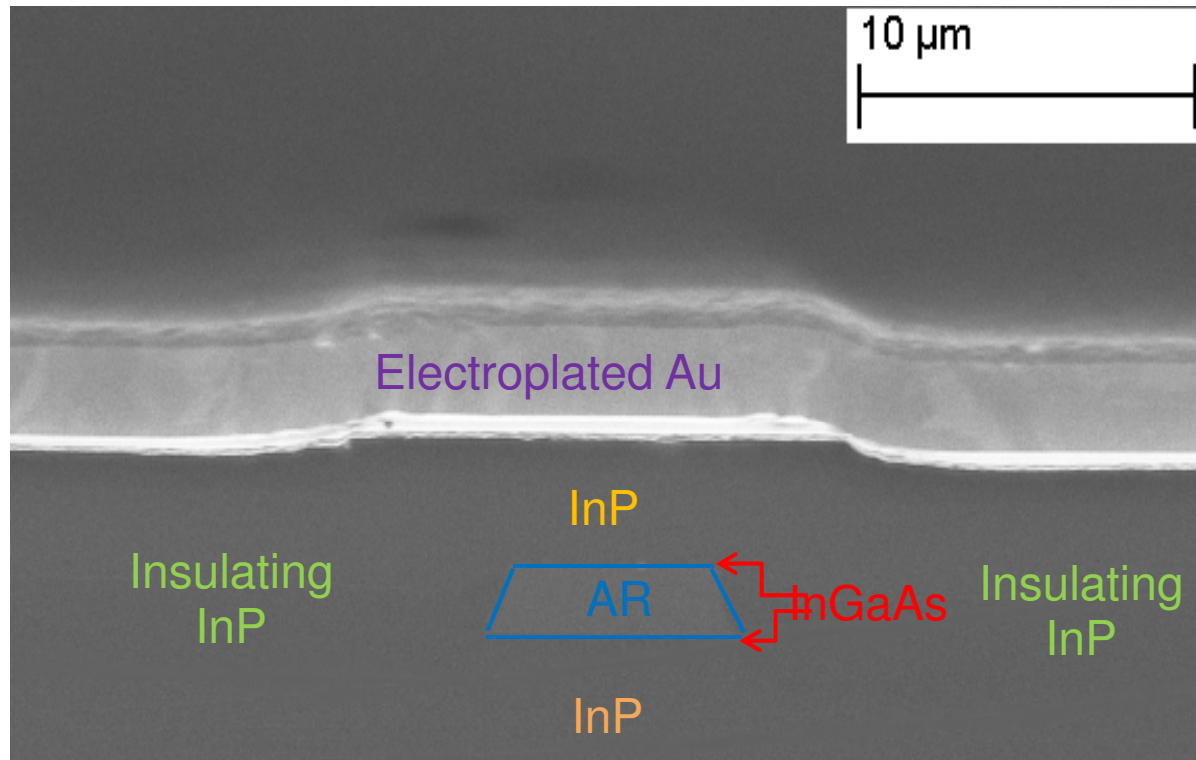
• opt power up to **48mW**
• $P_{\text{el}} \text{ max } \sim 1.4\text{W}$

Low-dissipation DFB devices at 5.25 μm

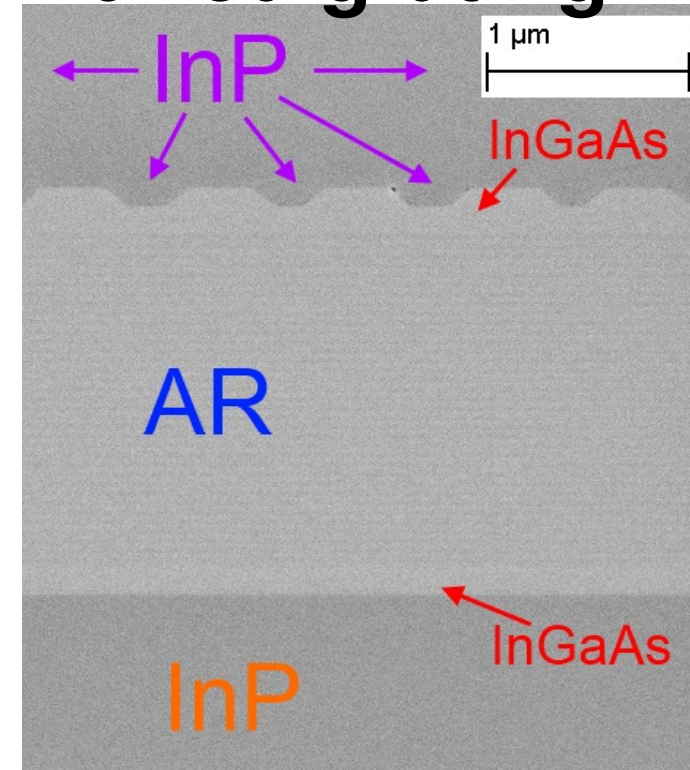


very low threshold power : 0.31W

Front facet



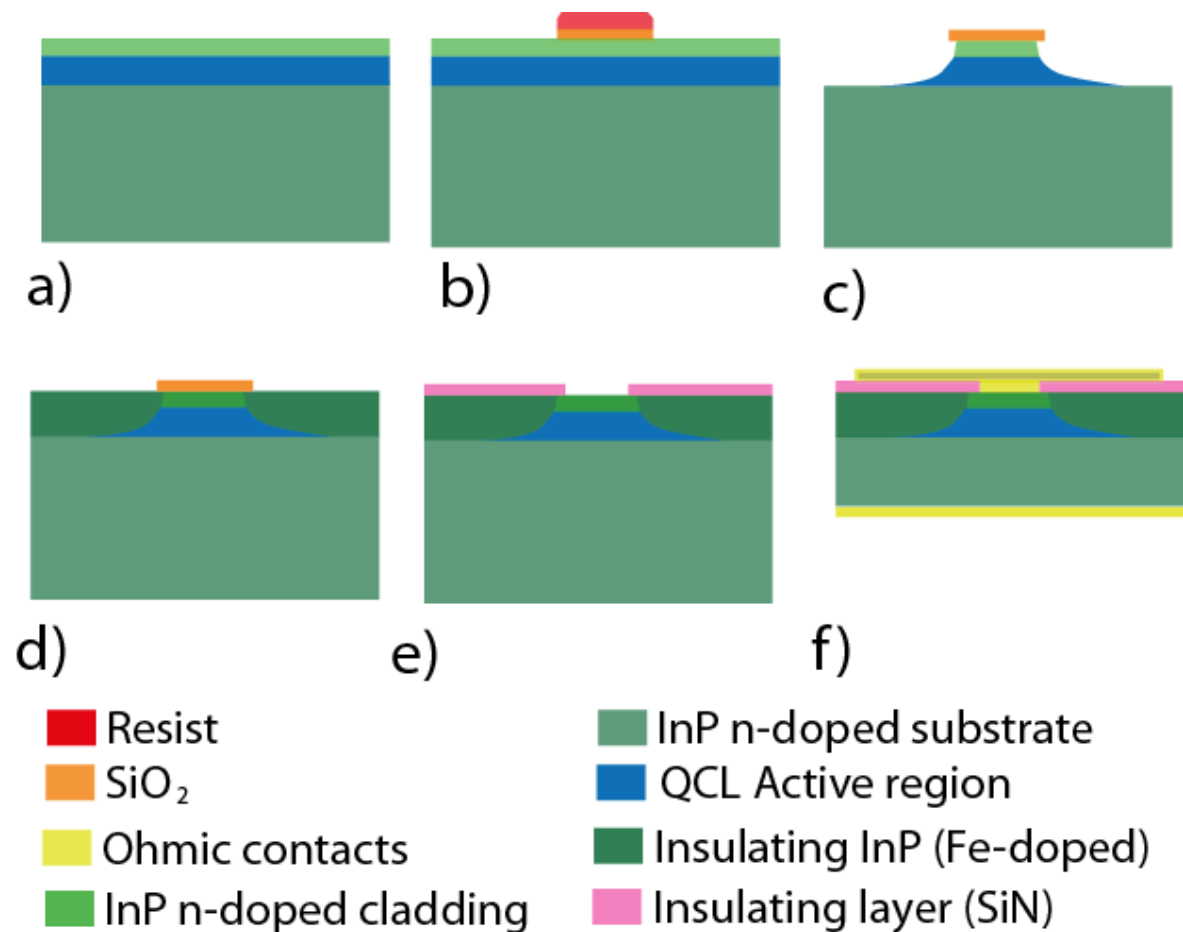
Buried grating



- .Most of QCLs have 5-15 W of electrical dissipation
- .Up to 100 W are needed to control the temperature

Importance of the fabrication process:

- .Optical losses
- .Thermal conductance
- .Device yield
- .Spectral purity (DFBs)





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